

mos fets

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D-MOS FET - SINGLE GATE | SD200 N-CHANNEL ENHANCEMENT

SD201 SD202

UHF AND GENERAL PURPOSE RF APPLICATIONS | SD203

DESCRIPTION

The Signetics D-MOS SD200/201/202/203 are silicon, insulated gate, field effect transistors of the N-channel enhancement mode type. They are fabricated by the Signetics double-diffused process which gives superior high frequency performance up to 2GHz. A zener diode is connected between the gate and substrate of the SD201 and 203 that bypasses any voltage transient lying outside the range of -0.3V to +25.0V. Thus the gates of the SD201 and 203 are protected against damage in all normal handling and operating situations.

All four devices are general purpose transistors especially suited for amplifier designs in the UHF range (500MHz to 2GHz). They have extremely high transconductance, very low input capacitance and extremely low feedback capacitance, The SD200, 201, 202 and 203 combine high gain with low levels of noise, intermodulation distortion and feedback capacitance. These parameters make them ideally suited for critical amplifier applications. These devices are hermetically sealed in modified 4-lead TO-72 packages.

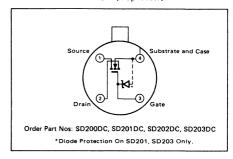
GENERAL FEATURES

- ION-IMPLANTED FOR GREATER CONTROL AND RELIABILITY
- WIDE DYNAMIC RANGE
- POSITIVE BIAS ONLY

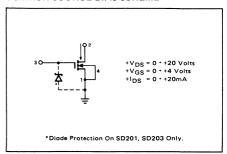
SD200/201 FEATURES

- ◆ HIGH GAIN THROUGH UHF RANGE 10dB AT 1GHz
- LOW NOISE THROUGH UHF RANGE: SD200 - 4.5dB SD201 - 5.0dB
- LOW INPUT CAPACITANCE 2.4pF
- LOW FEEDBACK CAPACITANCE 0.20pF
- HIGH DRAIN-TO-SOURCE VOLTAGE +30V
- HIGH FORWARD TRANSCONDUCTANCE 15,000 μ mhos

PIN CONFIGURATION (Top View)



COMMON SOURCE BLAS SCHEME



SD202/203 FEATURES

- HIGH GAIN THROUGH UHF RANGE 10dB AT 1 5GHz
- LOW NOISE THROUGH UHF RANGE 3.2dB AT 1.0GHz
- LOW INPUT CAPACITANCE 3.0pF
- LOW FEEDBACK CAPACITANCE 0.20pF
- HIGH DRAIN-TO-SOURCE VOLTAGE +25V
- HIGH FORWARD TRANSCONDUCTANCE 20,000 μmhos

+20V

50mA

ABSOLUTE MAXIMUM RATINGS

TA = 25°C (Unless Otherwise Noted)

DC Gate-To-Substrate Voltage (V_{GB})

 SD200
 ±40V

 SD201
 -0.3V, +10V

 SD202
 ±40V

 SD203
 -0.3V, +10V

Drain Current (I_D)

SD202/SD203

Ambient Temperature Range

Storage -65°C to +175°C

Operating -65°C to +125°C

Transistor Dissipation (PT)

At +25°C Case Temperature 1.2W (Derate linearly to +125°C case temperature at the rate of 8.0mW/°C.)

At $\pm 25^{\circ}$ C Free-Air Temperature 300mW (Derate linearly to $\pm 125^{\circ}$ C free-air temperature at the rate of ± 2.0 mW/ ± 0.0 C.)

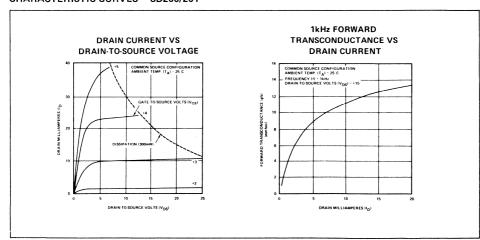
ELECTRICAL CHARACTERISTICS

T_A = 25°C (Unless Otherwise Noted)

	PARAMETER
BVDS	Drain-To-Source Breakdown Voltage
¹ GSS	Gate Leakage Current
I _D (OFF)	Drain-To-Source Current
IDSS	Zero Bias Drain Current
V _T	Threshold Voltage
gfs	Forward Transconductance
Small Sign	al Short Circuit
C _{ISS}	Input
Coss	Output
CRSS	Reverse Transfer
Gps	Power Gain*
NF	Noise Figure*
r _{DS} (ON)	Drain-To-Source On Resistance
P ₁	Intercept Point

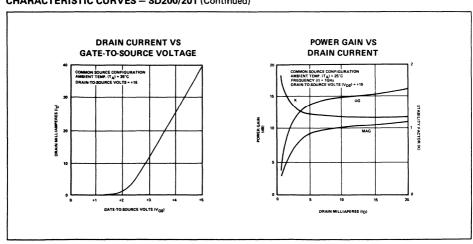
^{*}Measured In Amplifier Test Fixture

CHARACTERISTIC CURVES - SD200/201

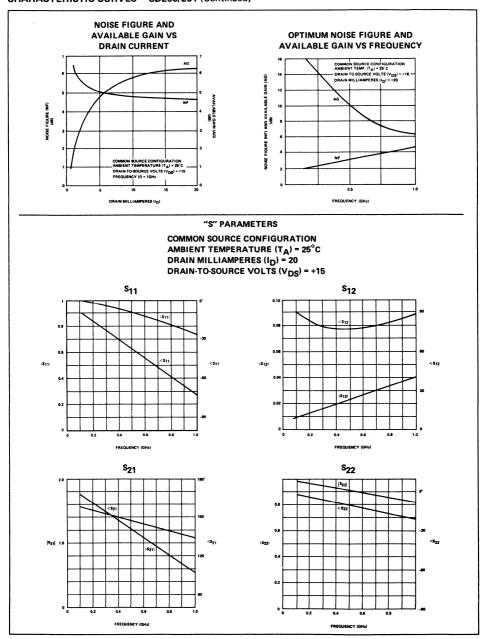


TEST CONDITIONS	SD200				SD201		1	SD202			SD203		
TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
V _{GS} = 0V, I _D < 1μA	25	30		25	30		20	25		20	25		V
V _{GS} = ±10V, V _{DS} = 0V V _{GS} = +10V, V _{DS} = 0V			0.1		0.001	1,0			0.1		0.001	1.0	nΑ μΑ
V _{DS} = +15V, V _{GS} = 0V		0.001	1.0		0.001	1.0		0.001	1.0		0.001	1.0	μΑ
V _{DS} = +15V, V _{GS} = 0V		0.001	1.0		0.001	1.0		0.001	1.0		0.001	1.0	μΑ
$V_{DS} = V_{GS} = V_T$, $I_D = 1\mu A$	0.1	1.0	2.0	0.1	1.0	2.0	0.1	1.0	2.0	0.1	1.0	2.0	V
V_{DS} = +15V, I_{D} = 20mA, f = 1kHz $V_{GS} \cong$ +4V $V_{GS} \cong$ +2.5V	13.0	15.0	-	13.0	15.0		17.0	20.0		17.0	20.0		mmhos mmhos
V _{DS} = +15V, f = 1MHz													
I _D = 20mA		2.4	3.0		2.4	3.0		3.0	3.6		3.0	3.6	pF
I _D = 0A		1.0	1.2		1.0	1.2		1.0	1.2		1.0	1.2	pF
I _D = 0A		0.20	0.30		0.20	0.30		0.20	0.30		0.20	0.30	pF
V_{DS} = +15V, I_D = 20mA, f = 1GHz V_{GS} \cong +4V V_{GS} \cong +2.5V	8	10		8	10		8	10		8	10		dB dB
V _{GS} ≅ +4V V _{GS} ≅ +2.5V		4.5	6.0		5.0	6.5		3.5	4.5		4.0	5.0	dB
V _{GS} = +5V, I _D = 5mA		50	70		50	70		35	50		35	50	Ω
V _{DS} = 15V, I _D = 20mA, f = 1GHz, Δf = 2MHz		29			29			29			29		dBM

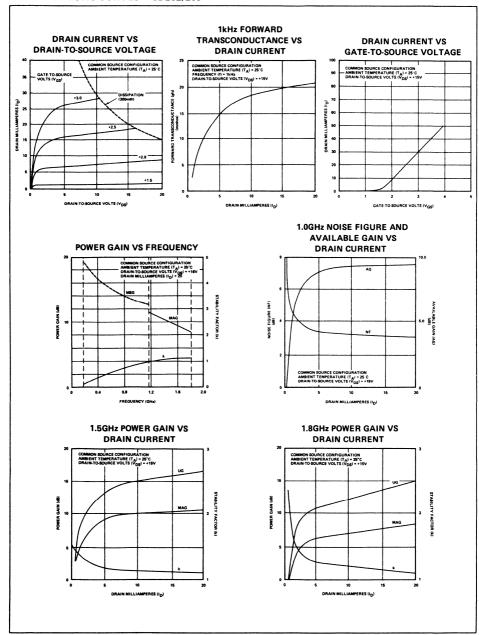
CHARACTERISTIC CURVES - SD200/201 (Continued)



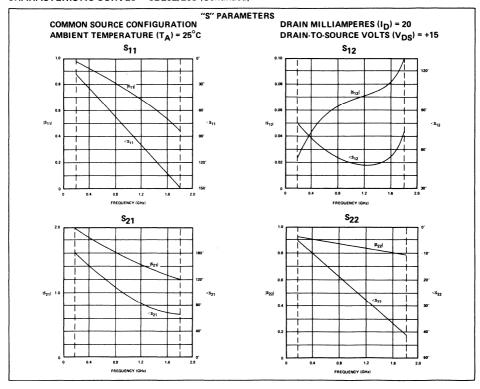
CHARACTERISTIC CURVES - SD200/201 (Continued)



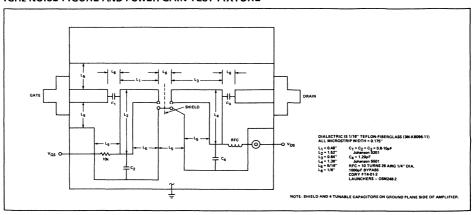
CHARACTERISTIC CURVES - SD202/203



CHARACTERISTIC CURVES - SD202/203 (Continued)



1GHz NOISE FIGURE AND POWER GAIN TEST FIXTURE



signetics

D-MOS FET SWITCH | SD210 N-CHANNEL ENHANCEMENT | SD211

ANALOG AND DIGITAL SWITCH AND SWITCH DRIVER APPLICATIONS

SD211 SD212 SD213 SD214 SD215

DESCRIPTION

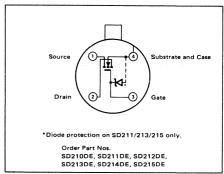
The Signetics D-MOS SD210, 211, 212, 213, 214 and 215 are silicon, insulated gate, field effect transistors of the N-channel enhancement mode type. They are fabricated by the Signetics double-diffused process which gives high switching speed and low capacitance. A zener diode is connected between the gate and substrate of the SD211, 213 and 215. The diode bypasses any voltage transients which lie outside the range of −0.3V to +25V. Thus, the gate is protected against damage in all normal handling and operating situations. A drain-to-source breakdown of typically 35V makes the SD210 and 211 ideally suited for ±10V switch driver applications. Other characteristics all the designed to switch signals up to ±10V and the SD212 and 213 are designed to switch signals up to ±5V.

All the devices feature low gate node capacitance, extremely low drain node capacitance and very low feedback capacitance. Low "ON" resistance and hermetically sealed 4-lead TO-72 packages are also featured.

FEATURES

- LOW FEEDBACK CAPACITANCE 0.30pF
- LOW DRAIN NODE CAPACÍTANCE 1.3pF
- LOW GATE NODE CAPACITANCE 2.4pF
- LOW FEEDTHROUGH AND FEEDBACK TRAN-SIENTS
- ION-IMPLANTED FOR GREATER RELIABILITY
- EXCELLENT ISOLATION FROM INPUT TO OUT-PUT – 120dB
- 35V DRAIN-TO-SOURCE VOLTAGE FOR SD210/211

PIN CONFIGURATION (Top View)



APPLICATIONS

SWITCH DRIVER
ANALOG SWITCH
MULTIPLEXERS
DIGITAL SWITCH
SAMPLE AND HOLD
CHOPPERS
A-TO-D CONVERTERS
D-TO-A CONVERTERS

ABSOLUTE MAXIMUM RATINGS TA = 25°C (Unless Otherwise Noted)

	PARAMETER	SD210	SD211	SD212	SD213	SD214	SD215	UNITS
VDS	Drain-to-Source	+30	+30	+10	+10	+20	+20	Vdc
v_{sd}	Source-to-Drain	+10	+10	+10	+10	+20	+20	Vdc
V_{DB}	Drain-to-Substrate	+15	+15	+15	+15	+25	+25	Vdc
V_{SB}	Source-to-Substrate	+15	+15	+15	+15	+25	+25	Vdc
V_{GS}	Gate-to-Source	±40	-15 +25	±40	-15 +25	±40	-25 +30	Vdc
V_{GB}	Gate-to-Substrate	±40	-0.3 +25	±40	-0.3 +25	±40	-0.3 +30	Vdc
V _{GD}	Gate-to-Drain	±40	-15 +25	±40	-15 +25	±40	-25 +30	Vdc

SIGNETICS D-MOS FET SWITCH - N-CHANNEL ENHANCEMENT ■ SD210-215

ABSOLUTE MAXIMUM RATINGS (All devices)

Drain Current (ID)

50mA

Ambient Temperature Range

Storage Operating -65°C to +175°C -65°C to +125°C

Transistor Dissipation (PT)

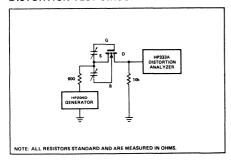
At 25°C Case Temperature

(Derate linearly to +125°C case temperature at the rate of 8.0mW/°C.) At 25°C Free-Air Temperature 300mW

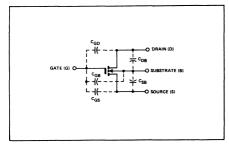
(Derate linearly to +125°C free-air temperature at the

rate of 2.0mW/°C.)

DISTORTION TEST CIRCUIT



CAPACITANCE MODEL



ELECTRICAL CHARACTERISTICS

	PARAMETER
Breakdown	Voltage
BV _{DS}	Drain-To-Source
BV _{SD}	Source-To-Drain
BV _{DB}	Drain-To-Substrate
BV _{SB}	Source-To-Substrate
Leakage Cur	rent

Leakage Current	
I _{DS} (OFF)	Drain-To-Source
I _{SD} (OFF)	Source-To-Drain
I _{GB}	Gate
V _T	Threshold Voltage
gfs	Forward Transconductance

Small Signal Capacitances (See Capacitance Model)

C(GS + GD + GB)	Gate Node
C(GD + DB)	Drain Node
C(GS + SB)	Source Node
C _{DG}	Reverse Transfer
r _{DS} (ON)	Drain-To-Source Resistance

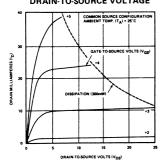
SIGNETICS D-MOS FET SWITCH - N-CHANNEL ENHANCEMENT ■ SD210-215

TEST COMPLITIONS		SD210)		SD211		SD212			SD213			SD214		SD215				
TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
$V_{GS} = V_{BS} = 0V, I_S = 10\mu A$ $V_{GS} = V_{BS} = -5V, I_S = 10nA$	30 10	35 25		30 10	35 25		10	25		10	25		20	25		20	25		v
V _{GD} = V _{BD} = -5V, I _D = 10nA	10			10			10			10			20			20			\ \
V _{GB} = 0V, Source OPEN, I _D = 10nA	15			15			15			15			25			25			V
$V_{GB} = 0V$, Drain OPEN, $I_S = 10\mu A$	15			15			15			15			25			25			v
	Τ			Γ						Γ		-	г—						
V _{GS} = V _{BS} = -5V V _{DS} = +10V V _{DS} = +20V		1	10		1	10		1	10		1	10		1	10	-	1	10	nA nA
$V_{GD} = V_{BD} = -5V$ $V_{SD} = +10V$ $V_{SD} = +20V$		1	10		1	10		1	10		1	10		1	10		1	10	nA nA
$V_{DB} = V_{SB} = 0V$ $V_{GB} = \pm 40V$ $V_{GB} = +25V$ $V_{GB} = +30V$			0.1		10				0.1		10				0.1		10		nA μA μA
$V_{DS} = V_{GS} = V_{T}, I_{S} = 1\mu A,$ $V_{SB} = 0V$	0.5	1.0	2.0	0.5	1.0	2.0	0.1	1.0	2.0	0.1	1.0	2.0	0.1	1.0	2.0	0.1	1.0	2.0	٧
V _{DS} = 10V, V _{SB} = 0V, I _D = 20mA, f = 1kHz	10	15		10	15		10	15		10	15		10	15		10	15		mmho
V _{DS} = 10V, f = 1kHz, V _{GS} = V _{BS} = -15V													***************						
		2.4	3.5		2.4	3.5		2.4	3.5		2.4	3.5		2.4	3.5		2.4	3.5	рF
		1.3	1.5		1.3	1.5		1.3	1.5		1.3	1.5		1.3	1.5		1.3	1.5	pF
		3.5	4.0		3.5	4.0		3.5	4.0		3.5	4.0		3.5	4.0		3.5	4.0	pF
		0.3	0.5		0.3	0.5		0.3	0.5		0.3	0.5		0.3	0.5		0.3	0.5	pF
$I_D = 0.1 \text{mA}, V_{SB} = 0$																			
V _{GS} = +5V	1	50	70		50	70		50	70	l	50	70		50	70		50	70	Ω
V _{GS} = +10V		30	45		30	45		30	45	1	30	45	1	30	45		30	45	Ω
V _{GS} = +15V V _{GS} = +20V	1	23 19			23 19		1	23 19		1	23 19			23 19			23 19		Ω
					19		1				19								Ω
V _{GS} = +25V		17			13			17			13			17			17		

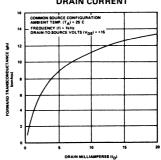
SIGNETICS D-MOS FET SWITCH - N-CHANNEL ENHANCEMENT ■ SD210-215

CHARACTERISTIC CURVES

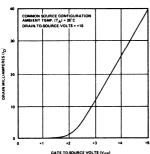




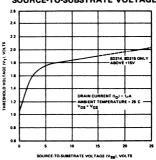
1kHz FORWARD TRANSCONDUCTANCE VS DRAIN CURRENT



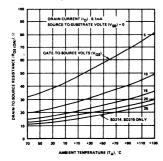
DRAIN CURRENT VS GATE-TO-SOURCE VOLTAGE



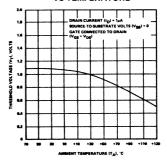
THRESHOLD VOLTAGE VS SOURCE-TO-SUBSTRATE VOLTAGE

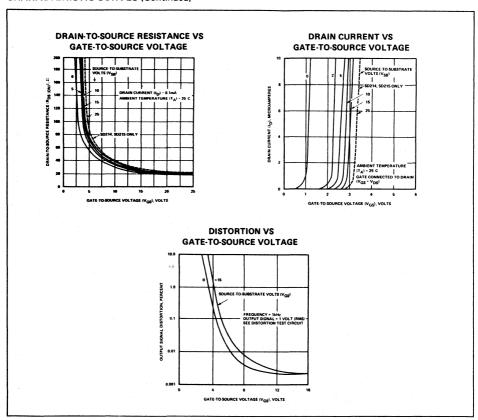


DRAIN-TO-SOURCE RESISTANCE VS TEMPERATURE

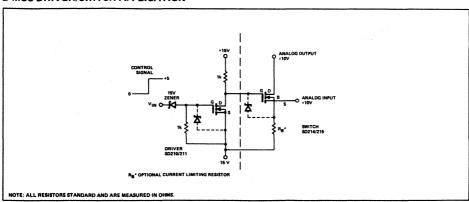


THRESHOLD VOLTAGE VS TEMPERATURE

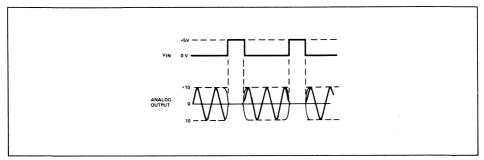




D-MOS DRIVER/SWITCH APPLICATION



TYPICAL WAVEFORMS

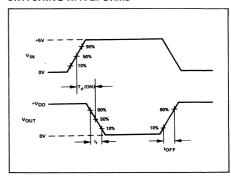


SWITCHING CHARACTERISTICS

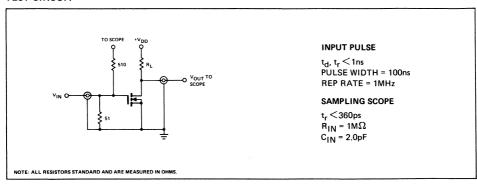
		t _d (O	N) (ns)	t _r	(ns)	t _{OFF} (ns)			
v_{DD}	RL	TYP MAX		TYP	MAX	TYP	MAX		
5	680	0.6	1.0	0.7	1.0	9.0	*		
10	680	0.7		0.8		9.0			
15	1k	0.9		1.0		14.0			

 $^{^{\}rm *t}_{\rm OFF}$ is dependent on R $_{\rm L}$ and C $_{\rm L}$ and does not depend on the device characteristics.

SWITCHING WAVEFORMS



TEST CIRCUIT





D-MOS FET DUAL GATE | SD300 **N-CHANNEL ENHANCEMENT**

SD301 SD303

VHF. UHF AND GENERAL PURPOSE RF APPLICATIONS

DESCRIPTION

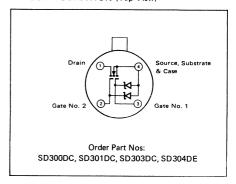
The Signetics D-MOS SD300/301/303/304 are silicon, dualinsulated-gate, field effect transistors of the N-channel enhancement mode type. They are fabricated by the Signetics double-diffused process which gives superior high frequency performance. Zener diodes are connected between the two gates and the substrate. These diodes bypass any voltage transients which lie outside the range of -0.3V to +25.0V. Thus, the gates are protected against damage in all normal handling and operating situations.

The devices' attributes make them ideally suited for a variety of high frequency amplifier and mixer applications. The presence of two gates plus the incorporation of the drift region in the structure, has made the feedback capacity (Crss) less than 0.02pF. A wide AGC capability plus a significant reduction in cross-modulation distortion is now available because of the inherent linearity of these devices. The SD300. 301, 303 and 304 are hermetically sealed in modified 4-lead TO-72 packages.

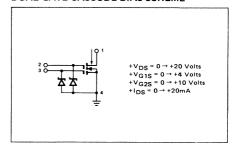
GENERAL FEATURES

- LOWER CROSS-MODULATION AND WIDER DYNA-MIC RANGE THAN BIPOLAR OR SINGLE GATE FETS
- REVERSE AGC CAPABILITY
- LINEAR MIXING CAPABILITY
- DIODE PROTECTED GATES
- HIGH FORWARD TRANSCONDUCTANCE afs = 10,000µmhos
- ION-IMPLANTED
- POSITIVE BIAS ONLY

PIN CONFIGURATION (Top View)



DUAL GATE CASCODE BIAS SCHEME



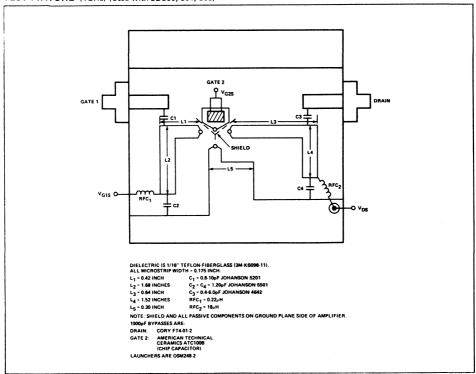
FEATURES

PARAMETER	SD300	SD301	SD303	SD304	UNIT
High Gain Through UHF Range	13	14	14		dB at 1GHz
High Gain Through VHF Range				16	dB at 500MHz
Low Noise Through UHF Range	8	6	5.5		dB at 1GHz
Low Noise Through VHF Range				5	dB at 500MHz
Low Input Capacitance	2.0	2.0	3.0	2.5	pF
Low Feedback Capacitance	0.02	0.02	0.02	0.03	pF
Low Output Capacitance	1.0	0.6	0.6	1.0	pF

ABSOLUTE MAXIMUM RATINGS

T _A = 25°C (Unless Otherwise Noted)		Ambient Temperature Range (TA)
Drain-To-Source (V _{DS}) SD300/304	+25V	Storage -65°C to +175°C Operating -65°C to +125°C
SD301	+20V	Transistor Dissipation (P _T)
DC Gate No. 1-To-Substrate Voltage (V _{G1B})	-0.3V,+10V	At +25°C Case Temperature 1.2W (Derate linearly to +125°C case temperature at the rate of 8.0mW/°C.)
DC Gate No. 2-To-Substrate Voltage (V _{G2B})	-0.3V, +15V	At +25°C Free-Air Temperature 300mW (Derate linearly to +125°C free-air temperature at the
Drain Current (I _D)	50mA	rate of 2.0mW/°C.)

TEST FIXTURE (1GHz) (Used With SD300, 301, 303)



ELECTRICAL CHARACTERISTICS TA = +25°C (Unless Otherwise Noted).

	PARAMETER	TEST CONDITIONS		SD300		SD301			D303	3	,	UNIT		
•	ANAMETER			TYP MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
B∨DS	Drain-To-Source Breakdown Voltage	V _{G1S} = V _{G2S} = 0V, I _D = 5μA	25	30	20	25		20	25	j	25	30		v
G1SS	Gate 1 Leakage Current	V _{G1S} = +5V, V _{G2S} = V _{DS} = 0V		0.001 0.1		0.001	0.1		0.001	0.1		0.001	0.1	μА

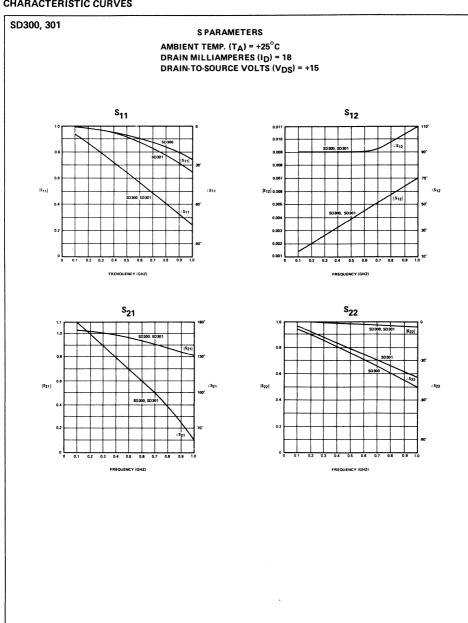
SIGNETICS D-MOS FET - DUAL GATE - SD300, SD301, SD303, SD304

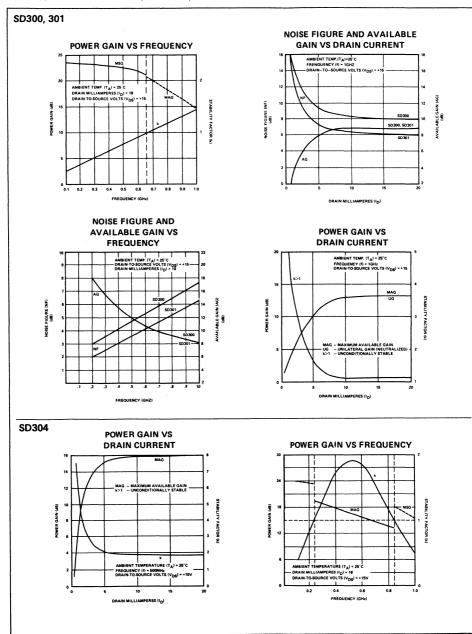
ELECTRICAL CHARACTERISTICS TA = +25°C (Unless Otherwise Noted), Continued

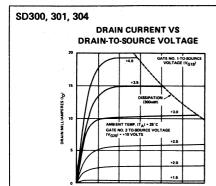
PARAMETER		TEST CONDITIONS		SD300		SD301		SD303			SD304			UNIT
				MIN TYP MAX		MIN TYP MAX		MIN TYP MAX			MIN TYP MAX			
0200	Gate 2 Leakage Current	V _{G2S} = +10V, V _{G1S} = V _{DS} = 0V		0.001 0.1		0.001	0.1		0.001	0.1		0.001	0.1	μА
	Drain-To-Source Leakage Current	V _{DS} = +15V, V _{G1S} = V _{G2S} = 0V		0.001 1.0		0.001	1.0		0.001	1.0		0.001	1.0	μА
	Zero Bias Drain Current	V _{DS} = +15V, V _{G1S} = V _{G2S} = 0V		0.001 1.0		0.001	1.0		0.001	1.0		0.001	1.0	μА
. 11	Gate 1 Threshold Voltage	V _{DS} = V _{G1S} = V _{T1} , V _{G2S} = +10V, I _D = 1μA	0.1	1.0 2.0	0.1	1.0	2.0	0.1	0.5	1.5	0.1	1.0	2.0	V
	Gate 2 Threshold Voltage	V _{DS} = V _{G2S} = V _{T2} , V _{G1S} = +4V, I _D = 1μA	0.1	1.0 2.0	0.1	1.0	2.0	0.1	0.5	1.5	0.1	1.0	2.0	V
Small Signal Short Circuit Capacitances		f = 1MHz, Gate 2 AC Grounded					-							
Ciss	Input	$\begin{split} &V_{DS} = +15V, V_{G1S} \cong 3.5V, \\ &V_{G2S} = +10V, I_{D} = 18mA \\ &V_{DS} = +15V, V_{G1S} \cong +2.5V, \\ &V_{G2S} = +10V, I_{D} = 18mA \\ &f = 1MHz \end{split}$		2.0 2.5		2.0	2.5		3.0	3.5		2.5	3.0	pF pF
Coss	Output	V _{DS} = +15V, V _{G1S} = 0V, V _{G2S} = +10V, f = 1MHz		1.0 1.2		0.6	8.0		0.6			1.0	1.2	ρF
Crss	Reverse Transfer	V _{DS} = +15V, V _{G1S} = 0V, V _{G2S} = +10V, f = 1MHz		0.02		0.02			0.02			0.03		pF
gfs	Forward Transconductance	V _{DS} = +15V, V _{G1S} ≥ +3.5V V _{G2S} = +10V, I _D = 18mA, f = 1kHz	8.0	10.0	8.0	10.0					8.0	10.0		mmhc
		V _{DS} = +15V, V _{G1S} ≅ +2.5V, V _{G2S} = +10V, I _D = 18mA						13.0	15.0					mmho
Gps	Power Gain	V _{DS} = +15V, V _{G1S} ≅ +3.5V, V _{G2S} = +10V, I _D = 18mA												
		f = 1GHz f = 500MHz f = 200MHz		13.0* 24.0		14.0° 25.0	•				13.0	16.0		dB dB dB
		V_{DS} = +15V, $V_{G1S} \approx$ +2.5V, V_{G2S} = +10V, I_{D} = 18mA, f = 1GHz						10.0	14.0	•				dB
NF	Noise Figure	V_{DS} = +15V, $V_{G1S} \cong$ +3.5V, V_{G2S} = +10V, I_D = 18mA												
		f = 1GHz f = 500MHz f = 200MHz		8.0*9.0 3.0 4.0			7.0 3.0					5.0	6.0	dB dB dB
		V _{DS} = +15V, V _{G1S} ≅ +2.5V, V _{G2S} = +10V, I _D = 18mA, f = 1GHz							5.5	7.0				dB
E _{int}	Interfering Signal Level At Gate For 1% Cross- Modulation Distortion. Peak	V _{DS} = +15V, V _{G2S} = +10V, I _D = 18mA, Desired Signal f = 500MHz, Undesired Signal f = 501MHz V _{DS} = +15V, V _{G2S} = +10V,		200		200			150			200		mV mV
	Voltage Referenced To 300Ω System.	ID = 18mA, Wanted Signal f = 1GHz, Interfering Signal f = 0.995GHz												
AGC (VG2S)	Range Of Automatic Gain Control	V_{DS} = +15V, V_{G1S} \approx +3.5V, f = 500MHz V_{DS} = +15V, V_{G1S} \approx +2.5V,		40		40			40			40		dB dB
	Drain-To-Source	f = 500MHz VG1S = +5V, VG2S = +10V,		90 130		90	130		65	80		90	130	Ω

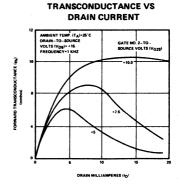
^{*}Measured in amplifier test fixture.

CHARACTERISTIC CURVES

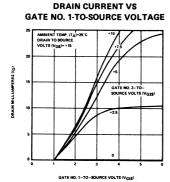




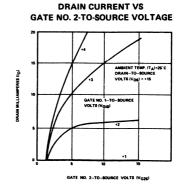


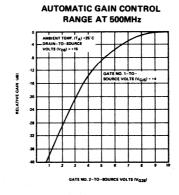


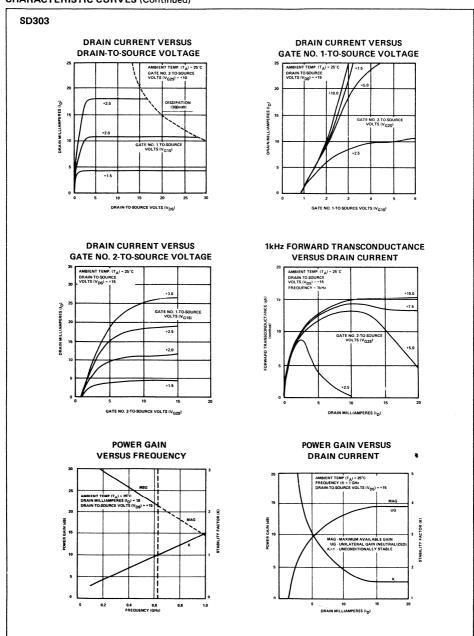
1kHz FORWARD



DRAIN-TO-SOURCE VOLTS (VDS)

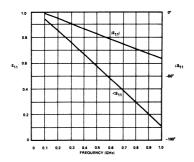


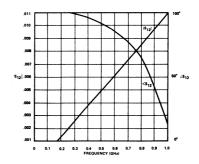


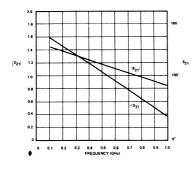


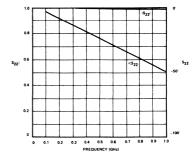
SD303

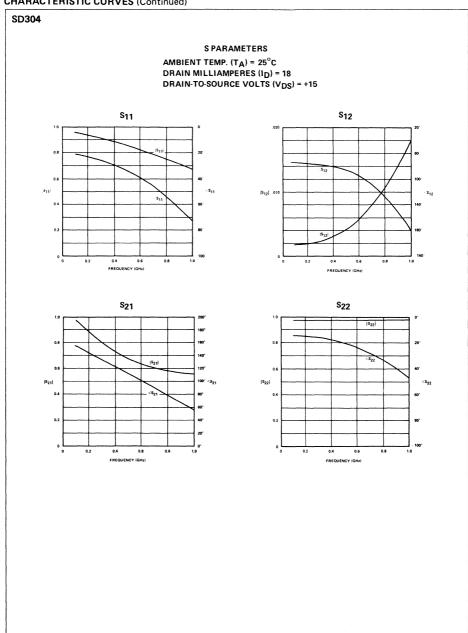
$S\,PARAMETERS\\ AMBIENT\,TEMP.\,\,(T_A)=+25^{\circ}C\\ DRAIN\,MILLIAMPERES\,\,(I_D)=18\\ DRAIN-TO-SOURCE\,VOLTS\,\,(V_{DS})=+15$













D-MOS FET - DUAL GATE | SD305 **N-CHANNEL ENHANCEMENT**

VHF TV AND FM APPLICATIONS

DESCRIPTION

The Signetics D-MOS SD305 and 306 are silicon, dualinsulated gate, field-effect transistors of the N-channel enhancement mode type. Zener diodes are connected between the two gates and the substrate. These diodes bypass any voltage transients which lie outside the range of -0.3V to +20.0V. Thus, the gates are protected against damage in all normal handling and operating situations.

The devices' attributes make them ideally suited for a variety of VHF amplifier and mixer applications. The presence of two gates plus the incorporation of the drift region in the structure has made the feedback capacity (CG1D) typically less than 0.03pF. A wide AGC capability plus significant reduction in cross modulation distortion is now available because of the inherent linearity of the devices. The SD305 and SD306 are hermetically sealed in a 4-lead TO-72 package.

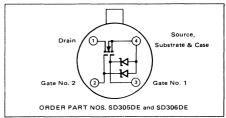
GENERAL FEATURES

- POSITIVE BIAS ONLY
- LOW GATE VOLTAGES
- ENHANCEMENT MODE OPERATION
- WIDE AGC RANGE 50dB AT 200MHz
- ZENER DIODE GATE PROTECTION
- ION IMPLANTED FOR GREATER RELIABILITY

FEATURES - SD305 (VHF TV and FM Mixer)

● HIGH CONVERSION GAIN - 17dB AT 200MHz WITH VG1S = VG2S FOR BIASING SIMPLICITY

PIN CONFIGURATION (Top View)



- EXCELLENT ISOLATION FROM GATE NO. 1 (RF) TO GATE NO. 2 (LO) - 20dB AT 200MHz
- LOW INPUT CAPACITANCE 4.0pF
- LOW FEEDBACK CAPACITANCE 0.03pF
- EXCELLENT CROSS MODULATION PERFORMANCE AND LOW NOISE OPERATION
- HIGH TRANSCONDUCTANCE 27mmhos

FEATURES - SD306 (VHF TV and FM RF Amplifier)

- HIGH POWER GAIN WITHOUT NEUTRALIZATION 20dB AT 200MHz
- LOW NOISE FIGURE 1.5dB AT 200MHz
- LOW INPUT AND OUTPUT CAPACITANCE 3.3pF AND 1.0pF CONSTANT WITH AGC
- LOW FEEDBACK CAPACITANCE 0.03pF
- SUPERIOR CROSS MODULATION PERFORMANCE
- HIGH TRANSCONDUCTANCE 15mmhos

ABSOLUTE MAXIMUM RATINGS TA = 25°C (Unless Otherwise Noted)

+20 -0.3 to +20	V Vdc
	Vdc
0.0 +- +20	1
-0.3 to +20	Vdc
50 50	mA
-65 to +175 -65 to +125	°c °c
1.2 300	W mW

ELECTRICAL CHARACTERISTICS TA = 25°C

PARAMETER		TEST CONDITIONS	SD305			SD306			UNITS	
		TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNITS	
OFF Char	racteristics									
BV _{DS}	Drain-To-Source Breakdown Voltage	$V_{G1S} = V_{G2S} = 0V,$ $I_D = 5\mu A$	20	30		20	25		V	
I _D (OFF)	Drain-To-Source Leakage Current	V _{DS} = +15V, V _{G1S} = V _{G2S} = 0V		0.001	1.0		0.001	1.0	μА	
I _{DSS}	Zero Bias Drain Current	V _{DS} = +15V, V _{G1S} = V _{G2S} = 0V		0.001	1.0		0.001	1.0	μΑ	
G1SS	Gate No. 1 Leakage Current	V _{G1S} = +5V, V _{G2S} = V _{DS} = 0V		0.001	0.1		0.001	0.1	μΑ	
I _{G2SS}	Gate No. 2 Leakage Current	$V_{G2S} = +10V,$ $V_{G1S} = V_{DS} = 0V$		0.001	0.1		0.001	0.1	μΑ	
ON Chara	cteristics		1		I				L	
V _{T1}	Gate 1 Threshold Voltage	$V_{DS} = V_{G1S} = V_{T1},$ $V_{G2S} = +10V, I_D = 1\mu A$	0.1	1.0	2.0	0.1	0.5	1.5	٧	
V _{T2}	Gate 2 Threshold Voltage	$V_{DS} = V_{G2S} = V_{T2},$ $V_{G1S} = +5V, I_D = 1\mu A$	0.1	1.0	2.0	0.1	0.5	1.5	٧	
r _{DS} (ON)	Drain-To-Source On Resistance	V _{G1S} = +5V, V _{G2S} = +10V, I _D = 0.1mA		30	60		65	100	Ω	
Small Sign	nal Characteristics		1	I	I.,	L		L	L	
gfs	Forward Transconductance	V _{DS} = +15V, V _{G2S} = +10V, f = 1kHz I _D = 50mA I _D = 18mA	24	27		13	15		mmhos mmhos	
gfs (CONV) Conversion Transconductance		V _{DS} = +15V, V _{G1S} = V _{G2S} , I _D = 8mA, f = 1kHz, E _{LO} (RMS) = 750mV		10					mmhos	
Capacitan	ces	f = 1MHz, Gate 2 AC Grounded								
C _{G1S}	Input	$V_{DS} = +15V, V_{G2S} = +10V$ $I_{D} = 50mA$ $I_{D} = 18mA$		4.0	5.0		3.3	3.6	pF pF	
		$V_{DS} = +15V, V_{G1S} = V_{G2S},$ $I_{D} = 8mA$		4.0	5.0				pF	
C _{DS}	Output	$V_{DS} = +15V,$ $V_{G1S} = 0V, V_{G2S} = +10V$		1.3	1.7		1.0	1.3	pF	
C _{G1D}	Reverse Transfer	$V_{DS} = +15V,$ $V_{G1S} = 0V, V_{G2S} = +10V$		0.03			0.03		pF	
Input Admittance			V _{G1S} = V _{G2S} , I _D = 8mA		V _{G2S} = +10V, I _D = 18mA					
Re (y ₁₁) Im (y ₁₁)				1.05 6.66			1.11 4.76			
Output Admittance Re (y ₂₂) Im (y ₂₂)		f = 200MHz, V _{DS} = +15V		0.73 2.09			1.05 1.54		mmhos	

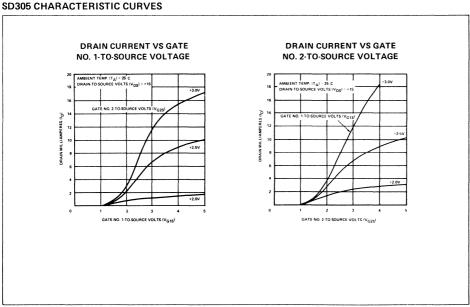
SIGNETICS D-MOS FET - DUAL GATE, N-CHANNEL ENHANCEMENT ■ SD305, SD306

ELECTRICAL CHARACTERISTICS (Continued) TA = 25°C

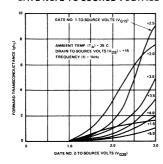
PARAMETER		TEST CONDITIONS	SD305			SD306			
			MIN	TYP	MAX	MIN	TYP	MAX	UNIT
Forward Transmittance Re (y_{21}) Im (y_{21})				4.69 -3.01			13.23 -5.62		
Reverse Transmittance Re (y ₁₂) Im (y ₁₂)				0.04 -0.03			0.01 -0.04		mmhos
G _{PS}	Power Gain ²	V _{DS} = +15V, V _{G2S} = +10V, I _D = 18mA, f = 200MHz				17	20		dB
G _{PS} (CON)	/)Conversion Power Gain ¹	V _{DS} = +15V, V _{G1S} = V _{G2S} , I _D = 8mA, f _{rf} = 200MHz, f _{LO} = 245MHz	14	17					dB
NF	Noise Figure	V _{DS} = +15V, V _{G2S} = +10V, I _D = 18mA, f = 200MHz					1.5	2.5	dB
AGC _{VG2S}	Range Of Automatic Gain Control	$V_{DS} = +15V, V_{G1S} \cong +2.5V,$ $V_{G2S} = +10V + 0V,$ f = 200MHz					50		dB
E _{INT}	Interfering Signal Level At Gate 1 For 1% Cross Modulation Distortion, Peak Voltage Referenced To 50Ω System ³	V_{DS} = +15V, V_{G2S} = +8V, I_D = 15mA, Wanted signal f = 200MHz Interfering signal f = 196MHz					480		mV

NOTES:

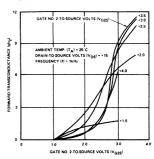
- 1. Measured in mixer test fixture.
- 2. Measured in amplifier test fixture.
- 3. Measured as shown in block diagram.



GATE NO. 1 FORWARD TRANSCONDUCTANCE VS GATE NO. 2-TO-SOURCE VOLTAGE

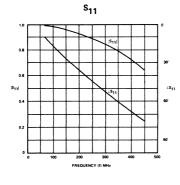


GATE NO. 2 FORWARD TRANSCONDUCTANCE VS GATE NO. 1-TO-SOURCE VOLTAGE

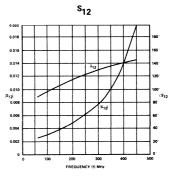


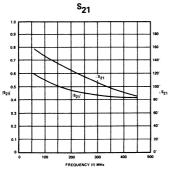
S PARAMETERS

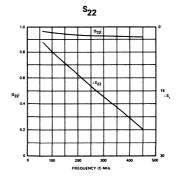
AMBIENT TEMP. (T_A) = +25°C DRAIN-TO-SOURCE VOLTS (V_{DS}) = +15



DRAIN MILLIAMPERES (I_D) = 8 GATE NO. 1-TO-SOURCE VOLTS = GATE NO. 2-TO-SOURCE VOLTS



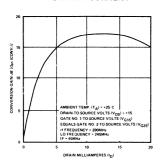




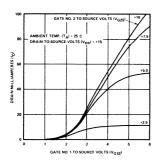
SIGNETICS D-MOS FET - DUAL GATE, N-CHANNEL ENHANCEMENT ■ SD305, SD306

SD305 CHARACTERISTIC CURVES (Continued)

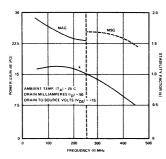
CONVERSION GAIN VS DRAIN CURRENT



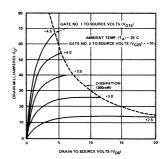
DRAIN CURRENT VS GATE NO. 1-TO-SOURCE VOLTAGE



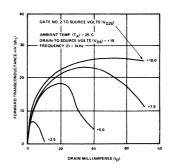
POWER GAIN VS FREQUENCY



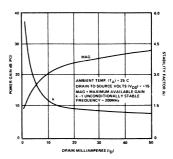
DRAIN CURRENT VS DRAIN-TO-SOURCE VOLTAGE

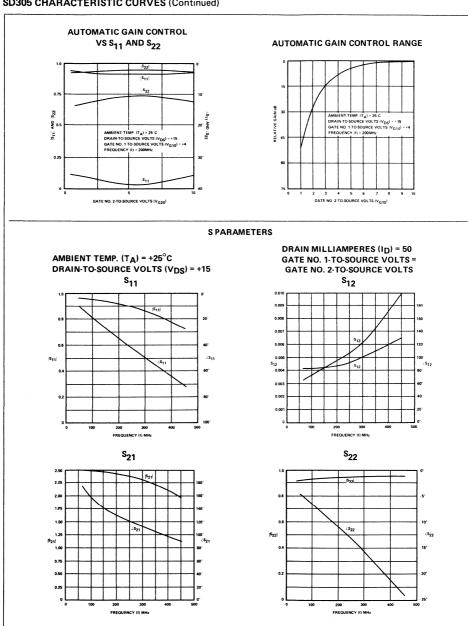


GATE NO. 1 FORWARD TRANSCONDUCTANCE VS DRAIN CURRENT



POWER GAIN VS DRAIN CURRENT

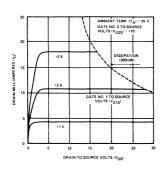




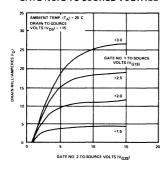
SIGNETICS D-MOS FET - DUAL GATE, N-CHANNEL ENHANCEMENT = SD305, SD306

SD306 CHARACTERISTIC CURVES

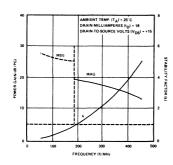
DRAIN CURRENT VS DRAIN-TO-SOURCE VOLTAGE



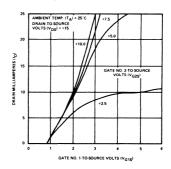
DRAIN CURRENT VS GATE NO. 2-TO-SOURCE VOLTAGE



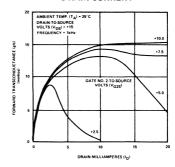
POWER GAIN VS FREQUENCY



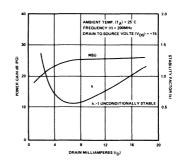
DRAIN CURRENT VS GATE NO. 1-TO-SOURCE VOLTAGE

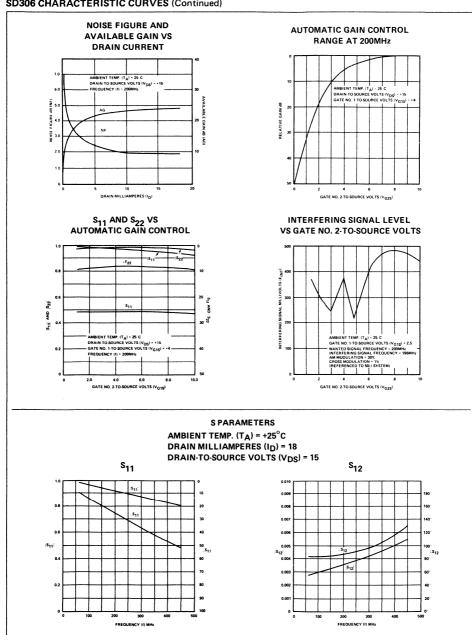


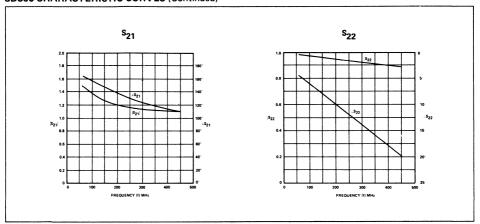
1kHz FORWARD TRANSCONDUCTANCE VS DRAIN CURRENT



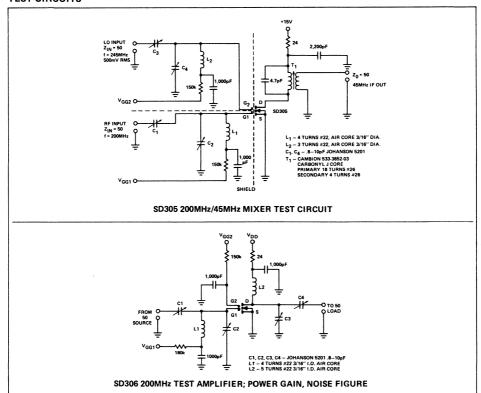
POWER GAIN VS DRAIN MILLIAMPERES







TEST CIRCUITS

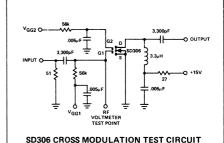


SD306

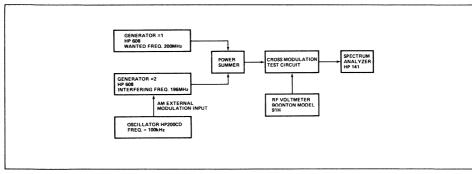
TEST PROCEDURE FOR CROSS MODULATION DISTORTION MEASUREMENTS

- 1. Modulation on Generator #2 is set at 100kHz, 30% AM modulation (sidebands down 15.6dB) with an output signal frequency equal to 196MHz.
- 2. Generator #2 is set at approximately 15dbm, 200MHz.
- 3. While observing the test circuit output spectrum, adjust the signal level of the interfering frequency so that the sidebands on the desired frequency are 46dB down from the carrier. This corresponds to 1% cross modulation.
- 4. Turn off Generator #1 and turn off the modulation on Generator #2.
- 5. Using the RF voltmeter, measure the amplitude of the interfering signal at the test point.

TEST CIRCUIT



BLOCK DIAGRAM OF CROSS MODULATION TEST



NOTES



APPLICATIONS MEMO SD305 SD306

A VOLTAGE TUNED VHF TV TUNER

SYSTEM DESIGN

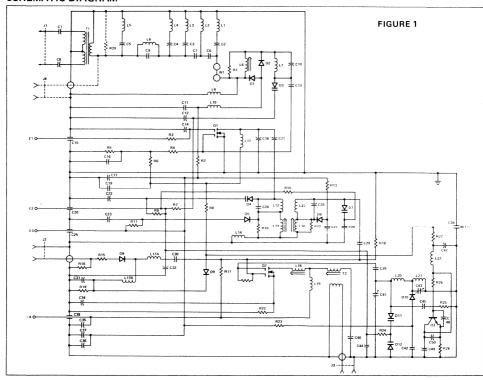
Television set manufacturers generally specify the requirements for tuners to be incorporated in their sets. The familiar turret tuner has served the industry and the consumer well over the past years. However, these tuners have an inherent disadvantage in that the contacts become dirty and worn resulting in an expensive service call and subsequent customer dissatisfaction. The advent of the voltage variable semiconductor capacitor now makes it feasible and economically possible to produce a contactless all solid state television tuner.

Set manufacturers generally require about 30dB overall gain with AGC gain reductions to 50dB. Acceptable noise figures range from 3 to 8dB. Cross modulation performance has also recently been of greater concern particularly in regard to what is known as the channel 6 color beat, Image and IF rejection specifications are also strictly adhered to. Some other requirements in regard to oscillator radiation are controlled by the FCC. These and others to be made evident requirements are met for a VVC VHF tuner by the following design:

ANTENNA FILTER

To improve crossmodulation, image and IF rejection performance an RF antenna filter is included. This consists of two cascaded filters: one a band stop filter to attenuate the FM band, the other a high pass with cut-off just below channel 2. This filter is shown in Figure 1 and consists of C3 through C9 and L1 through L6. It may easily be designed from handbook formulas,

SCHEMATIC DIAGRAM



SYSTEM DESIGN (Continued)

RF STAGE

From an economic standpoint, it is possible to use only one active device in this stage. Therefore a device giving large RF gain is sought as a primary requirement. If the device itself has a low noise figure, the large gain it offers will overcome the generally poor noise figure of the subsequent mixer stage. AGC voltage will be applied only to the RF stage. A desirable feature here is that the AGC voltage remain unipolar, that is, the voltage should not cross zero anywhere in the controlled range. The Signetics SD306 is an admirable performer in this regard.

An impedance matching network is required following the 75 ohm antenna filter. This provides a conjugate match to the input impedance at gate 1 of the dual gate MOS FET. The network is electronically tuned by a voltage variable capacitor to maintain the matched condition for each channel. Since the capacitance range of the varactor (VVC), D3 in Figure 1 is limited, the entire VHF band cannot be tuned. Therefore an electrically controlled band switch is used and the matching network is divided. In Figure 1, pin diodes D1 and D2 short circuit L8 and place L10 in parallel with L9 for the high band. For the low band L7 is in series with L8 and L10 is not connected when the diodes are nonconducting.

Adequate bypassing of a source resistor in the usual RF amplifier is always an attendant problem especially on a printed circuit layout. The design of the SD306 allows the omission of the source resistor and its bypass. The source terminal of this FET may therefore be directly grounded for minimum undesirable feedback impedance.

INTERSTAGE

The interstage provides the greatest selectivity since it consists of a double tuned network. The low band network contains a complex coupling scheme to control bandwidth as the circuit is tuned. The coupling consists of L14 in Figure 1 and the stray capacitance between the primary and secondary coils and printed wiring. This results in nearly constant bandwidth over the entire low band but the degree of overcoupling varies as shown in Figure 2, the RF interstage responses. This however is not detremental since the single tuned antenna circuit response will fill this in as shown in Figure 3, the overall RF responses.

Diodes D5 and D6 form a bandswitch which short the low band coils, L13, L14, and L16 and leave the high band coils, L12 and L15 active. The mutual coupling in this case is largely electromagnetic. The high band RF responses are also shown in Figures 2 and 3.

MIXER - IF AMPLIFIER

The mixer for this design has an additional function in that it must serve as an IF amplifier for the companion UHF tuner. The biasing arrangement is therefore a compromise between best operation as a mixer and a straight IF amplifier. When gate 2 is used for oscillator injection, the differences in biasing between the two modes of operation

are not large. When gate 2 is used for oscillator injection, two additional performance advantages are realized. One is that the bias for the device is simplified because gate 1 and gate 2 can be at the same potential. The other advantage is that there will be greater than 20dB isolation between the local oscillator and the RF input. This minimizes LO radiation out of the antenna terminals.

The UHF IF input circuit is a double tuned "low side C" scheme where L17A in Figure 1 is one coil while the other is located in the UHF tuner. The coupling capacitor consists partly of the interconnecting coaxial cable. This circuit is detuned when UHF is not used by diode D9 and L17B.

The mixer output circuit is also a double tuned network for increased selectivity to reject oscillator frequency especially on the low frequency channels.

OSCILLATOR

The use of a dual gate MOS FET as mixer for improved crossmodulation characteristics usually requires large oscillator voltage swings to achieve efficient mixing action. A bipolar mixer will need 100 to 200 millivolts injection compared to 1 to 3 volts injection for a typical dual gate MOS FET. This requirement is overcome by using the SD305 which requires only 500mV injection.

The oscillator design is a straightforward ordinary common collector Colpitts type. The oscillator tuning diodes are placed back-to-back to cancel some inherent nonlinearities associated with their large signal operation. Oscillator tracking is achieved by use of only trimmer capacitors in both bands. The low band tracking could be improved with the addition of a padder capacitor but this requires a trimmer of value less than the stray capacitance in the circuit and is therefore not feasible. The RF bandwidth has been made sufficiently broad in the low band to accomodate the tracking error.

SCHEMATIC DIAGRAM

Item

Figure 1 is the schematic diagram of the complete voltage variable capacitor VHF television tuner. Shown at the left hand side are two alternate modes of input connection, either 300 ohm balanced or 75 ohm unbalanced. This is followed by the antenna input filter, the input matching network, and the active device. These elements comprise the first shielded compartment of the tuner. The second compartment contains only the double tuned interstage network and the input network for the IF of the UHF companion tuner. The third compartment contains the mixer and local oscillator. The IF output is taken from this compartment.

CONNECTOR AND TERMINAL DESIGNATIONS

E1	AGC	terminal.	0-10	VDC.	Max.	gain	at 1	10	VDC.

Description

E2 Tuning Voltage Terminal, 2-25 VDC.

CONNECTOR AND TERMINAL DESIGNATIONS

(Continued)

Item	Description
E3	Band Switch Terminal, low band -2 to -20 VDC, high band +20 VDC.
E4	Mixer B+ terminal, +20 VDC.
E5	RF and Local Oscillator B+ Terminal, +20 VDC.
J1	300 ohm balanced line antenna input terminal.
J2	UHF Tuner IF Input Terminal.
J3	43.5 MHz IF Output Terminal.
J4	75 ohm unbalanced Line Antenna Input Terminal (optional).

ALIGNMENT

Except for the oscillator, on variable trimmer capacitors have been used in the RF circuits of this design. In a printed circuit design the stray capacitances due to the wiring do not vary much between units, the VVC's are purchased in matched sets, and the interelectrode capacitances of the active devices are only a fraction of the total shunt circuit capacity. The active device capacitance variations between units would be the only reason for the use of trimmers and since this is only a fraction of the total any resulting detuning will be small and can be compensated by the variation of the inductors.

ANTENNA FILTER ALIGNMENT

All components of this filter are mounted on the same printed circuit as the tuner components. To accurately align this filter, it must not be connected as its output to any tuner component. Therefore a jumper wire replaces a connection on the printed circuit. This jumper is replaced after alignment of the filter. The filter is aligned with sweep frequency techniques using appropriate marker frequencies.

The turns of free standing coils are separated as appropriate to affect tuning of each filter element. The coils are initially wound for slightly too large an inductance.

INTERSTAGE FILTER ALIGNMENT

It is generally necessary to align the interstage before the input matching network. The input network is swamped

with a low value resistance so that it does not effect the interstage response. The mixer output circuit is also similarly swamped. The RF response is then viewed with sweep frequency techniques using the mixer source terminal as a connection point to the vertical amplifier of the oscilloscope. Responses as shown in Figure 2 should be achieved. The low band coils are provided with adjustable cores while the high band adjustments are made by pushing the coil turns.

INPUT MATCHING NETWORK

Removal of the input swamping resistor will allow this network to be tracked to the interstage response achieved above. The results as shown in Figure 3 should be achieved.

MIXER OUTPUT CIRCUIT

In this case the interstage network is swamped with a resistance and the IF alignment frequency is introduced across the interstage network. The output swamping resistor used in the above alignment is removed from the IF output network and this circuit is aligned to a maximally flat response at the IF frequency. The IF output terminal is used as a point of measurement in this case.

OSCILLATOR TRACKING

The oscillator is made to track the RF circuits just aligned by adjusting the L-C ratio so that the oscillator is exactly 43.5 MHz above the RF at the end channels of both bands. This results in a small deviation in the band centers, but the RF bandwidths are sufficiently broad to accommodate this error. The overall responses should appear as shown in Figure 4.

PERFORMANCE

The essential performance characteristics are tabulated below. This data was taken for a tuner which used the SD304 for the RF amplifier and mixer. The tuner was later modified to use the SD305 and SD306. Complete data has not been completed at the present time. However, a pre-liminary look showed a 3-4dB improvement in gain and a

Channel	Gain	Gain*	NF	NF*	VSWR	V _{tune}	Gain Red.	Image Rej.
2	31.5		5.2		2.1	2.50	66	70
3	31	33	4.8	2.9	1.9	4.22	65.5	70
4	32		4.7		2.3	5.96	64	70
5	31.5		4.8		1.9	11.15	63	70
6	31		4.8		1.7	23.5	61.5	70
7	26		5.1		2.1	6.28	60	70
8	26.5		4.9		2.3	7.34	58	65
9	27		4.7		2.1	8.52	56.5	64
10	27		4.6		1.9	9.98	56	61
11	27		4.7		1.9	12.07	55	63
12	27.5	30	4.6	4.0	1.9	15.58	54.5	65
13	27.5		4.8		1.9	24.0	54	65

^{*}SD305/306 Tuner.

PERFORMANCE (Continued)

1-2dB reduction in noise figure. A preliminary look at crossmodulation for the channel 6 color beat indicated it to be 60dB down for an input level of one millivolt for each of the channel 6 carriers. Input VSWR was somewhat in excess of 3 with the input circuit as shown in Figure 1. This is partly due to oscillator mistracking in the low band. Since the schematic was drawn a damping resistor of 3.3k was added across L8 to reduce the VSWR to the figures in the tabulation.

CONSTRUCTION

The tuner chassis consists mechanically of a one inch wide strip of sheet metal formed into a U-shaped frame with ears bent outwardly. The ears serve as a mounting base. Phono jack connectors are soldered into appropriate holds on this frame and are connected to respective points on the printed

circuit board. The open end of the U-shaped frame is closed with another one inch flat strip soldered at its ends to the U-frame. This strip contains the five feedthrough capacitors which form the external connection points.

The printed circuit board rests on kicked out tabs of the frame and is soldered to the inside wall of the frame at several places around the periphery. Two shields separate the various stages and provide ground connections to several points on the printed circuit which would be inaccessible otherwise. To avoid making each of the shields of two pieces, one for each side of the printed circuit board, long tabs of a one piece shield extend through slots in the board to contact the cover on one side while the opposite end of the shield contacts the cover on the other side. The covers are made with fingers bent at greater than a right angle all along the edge of the cover.

PARTS LIST

CAPACITORS

			Lead		
Item	Value	Description	Spacing	Mepco/Electra #	Standard #
C1	450 pF	Ceramic Disc	0.25"	na	
C2	450	Ceramic Disc	0.25	na	
C3	3.9	Ceramic Plate	0.1	2222 641 09398	
C4	56	Ceramic Plate	0.1	2222 641 10569	
C5	3.9	Ceramic Plate	0.1	2222 641 09398	
C6	27	Ceramic Plate	0.1	2222 641 10279	
C7	27	Ceramic Plate	0.1	2222 641 10279	
C8	27	Ceramic Plate	0.1	2222 641 10279	
C9	27	Ceramic Plate	0.1	2222 641 10279	
C10	1,000	Ceramic Plate	0.1	2222 629 05102	
C11	3.9	Ceramic Plate	0.1	2222 641 09398	
C12	1,000	Ceramic Plate	0.1	2222 629 05102	
C13	1,000	Ceramic Plate	0.1	2222 629 05102	
C14	1,000	Ceramic Plate	0.1	2222 629 05102	
C15	1,000	Ceramic Plate	0.2	2222 629 06102	
C16	1,000	Ceramic Plate	0.1	2222 629 05102	
C17	1,000	Ceramic Feedthru	_	na	
C18	1,000	Ceramic Plate	0.1	2222 629 05102	
C19	1	Ceramic Plate	0.1	2222 641 03108	
C20	1,000	Ceramic Plate	0.2	2222 629 06102	
C21	1,000	Ceramic Plate	0.2	2222 629 06102	
C22	1,000	Ceramic Plate	0.2	2222 629 06102	
C23	1,000	Ceramic Feedthru		na	
C24	3.3	Ceramic Plate	0.1	2222 641 09338	
C25	1.8	Ceramic Plate	0.1	2222 641 03188	
C26	1,000	Ceramic Feedthru	_	na	
C27	1,000	Ceramic Plate	0.2	2222 629 06102	
C28	1,00G	Ceramic Plate	0.2	2222 629 06102	
C29	8.2	Ceramic Plate	0.2	2222 642 09828	
C30	22	Ceramic Plate	0.1	2222 641 10229	
C31	4,700	Ceramic Plate	0.1	2222 629 05472	
C32	4,700	Ceramic Plate	0.2	2222 629 06472	
C33	4,700	Ceramic Plate	0.1	2222 629 05472	
C34	1,000	Ceramic Plate	0.1	2222 629 05102	
C35	1.5	Ceramic Plate	0.1	2222 641 03158	

PARTS LIST (Continued)

CAPACITORS

			Lead		
Item	Value	Description	Spacing	Mepco/Electra #	Standard $\#$
C36	1pF	Ceramic Plate	0.1"	2222 641 03108	
C37	10,000	Ceramic Plate	0.1	2222 629 05103	
C38	1,000	Ceramic Plate	0.2	2222 629 06102	
C39	1,000	Ceramic Feedthru	_	na	
C40	0.5-3	Ceramic Tubular Trimmer		na	
C41	1,000	Ceramic Plate	0.1	2222 629 05102	
C42	1,000	Ceramic Plate	0.1	2222 629 05102	
C43	0.5-3	Ceramic Tubular Trimmer		na	
C44	2.7	Ceramic Plate	0.1	2222 641 09278	
C45	1,000	Ceramic Plate	0.1	2222 629 05102	
C46	1,000	Ceramic Feedthru	-	na	
C47	10	Ceramic Plate	0.1	2222 641 10109	
C48	1,000	Ceramic Plate	0.2	2222 629 06102	
C49	1,000	Ceramic Plate	0.1	2222 629 05102	
C50	8.2	Ceramic Plate	0.1	2222 641 09828	

CHOKES AND COILS

		Winding	Wire			
Item	# Turns	Direc.	No.	I.D.	Coil Form	Core
L1	13 1/2	L	26	0.213"	na	na
L2	3 1/2	R	24	0.130	na	na
L3	13 1/2	L	26	0.213	na	na
L4	10 1/2	R	26	0.213	na	na
L5	7 1/2	L	24	0.150	na	na
L6	10 1/2	R	26	0.213	na	na
L7	3 1/2	R	24	0.130	na	na
L8	8 1/2	R	24	_	0.166 O.D. paper	J, 6-32 X 1/4
L9	7 1/2	L	24	0.150	na	na
L10	2 1/2	R	24	0.130	na	na
L11	30	L	34 NY CEL	0.156	na	na
L12	3 1/2	L	22	0.150	na	na
L13	11 1/2	R	24	_	0.166 O.D. paper	J, 6-32 X 1/4
L14	4 1/2	L	24	0.150	na	na
L15	3 1/2	R	22	0.150	na	na
L16	8 1/2	L	24	_	0.166 O.D. paper	J, 6-32 X 1/4
L17A	12 1/2	R	34	_	0.25 O.D. polyprop	J, 10-32 X 5/16
L17B	12 1/2	R	34		On same form at opposite end	
L18	25	R	30	_	0.25 O.D. polyprop	J, 10-32 X 5/16
L19	15 1/2	L	26	0.166	na	na
L20	3 1/2	L	24	0.150	na	na
L21	6 1/2	R	24		0.166 O.D. paper	J, 6-32 X 1/4
L22	30	L	34 NY CEL	0.156	na	na

TRANSFORMERS

T1 300 ohm balanced to 75 ohm unbalanced trifilar wire on small toroidal core (details not available at this time)

T2	25 (pri.)	L	30	-	0.25 O.D. polyprop	J, 10-32 X 5/16
	3 (sec.)	R	28	-	(Wound over cold side of primary)	

SIGNETICS A VOLTAGE TUNED VHF TV TUNER = SD305, SD306

PARTS LIST (Continued)

R	ES	IST	o	RS	;
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All resistors are 1/4 watt carbon composition of carbon film types.

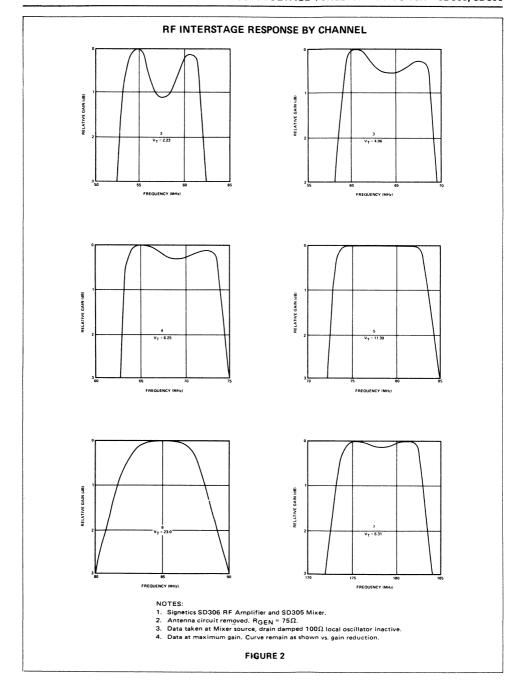
,.		
Item	Value	Tolerance
R1	1,500	10%
R2	22,000	20
R3	56,000	5
R4	47,000	20
R5	220,000	5
R6	470	10
R7	47,000	20
R8	47,000	20
R9	115,000	5
R10	3,300	10
R11	10,000	20
R12	27	5
R13	3,300	5
R14	3,300	10
R15	47,000	20
R16	39,000	5
R17	3,300	10
R18	47,000	5
R19	220,000	5
R20	470	5
R21	33,000	5
R22	3,300	10
R23	10,000	5
R24	10,000	10
R25	10,000	5
R26	330	10
R27	1,000	5
R28	680,000	20

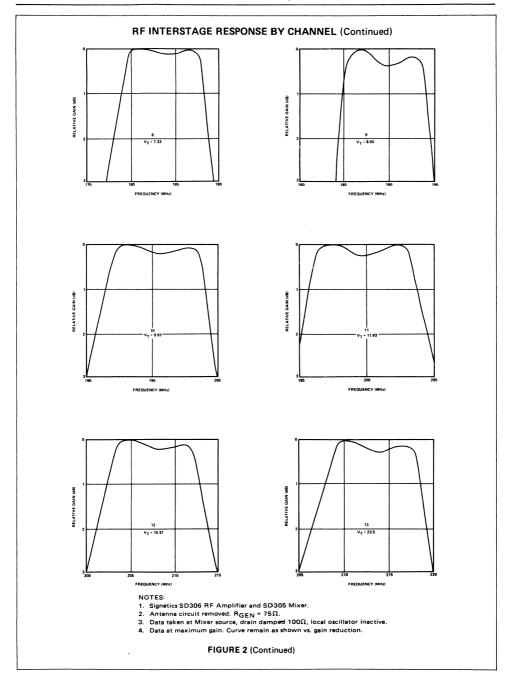
NOTE:

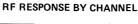
R28 is used only with the 75 ohm input model in which case T1 is omitted.

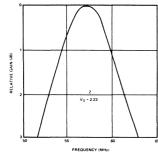
SEMICONDUCTORS

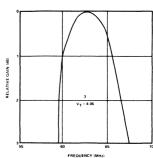
Item	Manufacturer	Part No.
Q1	Signetics	SD306
Q2	Signetics	SD305
Q3	Motorola	MPS HII
D1	Motorola	MPN3401
D2	Motorola	MPN3401
D3	ITT	BB105G
D4	ITT	BB105G
D5	Motorola	MPN3401
D6	Motorola	MPN3401
D7	Motorola	MPN3401
D8	ITT	BB105G
D9	ITT	1N4148
D10	Motorola	MPN3401
D11	ITT	BB105G
D12	ITT	BB105G

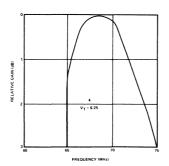


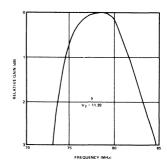


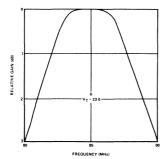


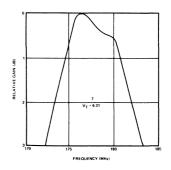








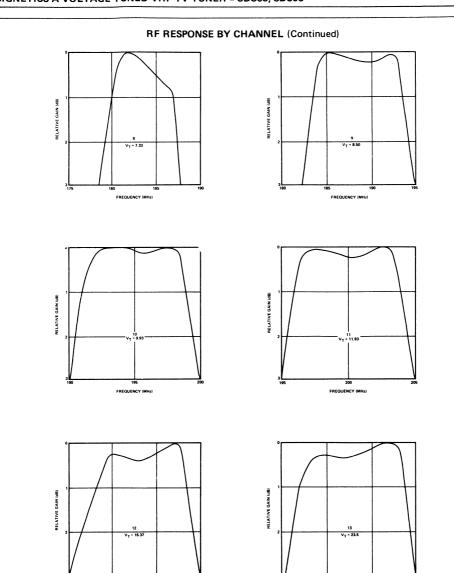




NOTES:

- Signetics SD306 RF Amplifier and SD305 Mixer.
- 2. Data taken at Mixer source, drain damped 100Ω , local oscillator inactive.
- 3. Data at maximum gain. Curves for CH2 and 3 become more peaked with gain reduction. Others remain essentially as shown.

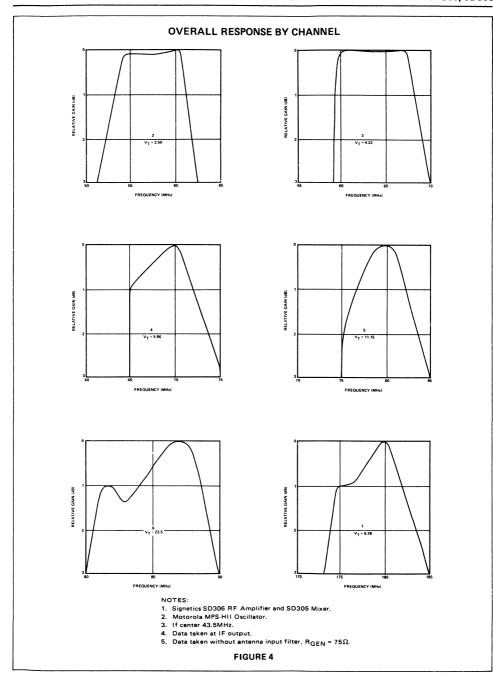
FIGURE 3

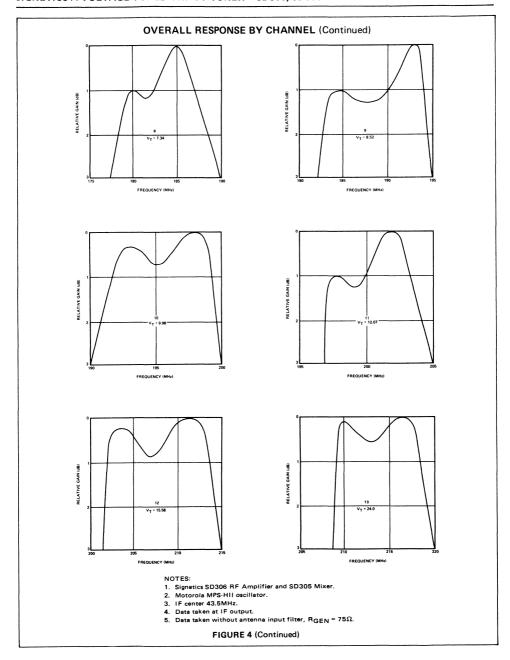


NOTES:

- 1. Signetics SD306 RF Amplifier and SD305 Mixer.
- 2. Data taken at Mixer source, drain damped 100 $\!\Omega$ local oscillator inactive.
- 3. Data at maximum gain. Curves for CH2 and 3 become more peaked with gain reduction. Others remain essentially as shown.

FIGURE 3 (Continued)





D-MOS FET QUAD ANALOG SWITCH ARRAYS, | SD5000 **MULTIPLEXERS AND DRIVER | SD5001**

ANALOG SWITCHING AND DRIVER SD5100 APPLICATIONS | SD5101

DESCRIPTION

The Signetics D-MOS SD5000, 5100 and 5200 series are monolithic arrays of silicon, insulated-gate, field-effect transistors using the N-channel enhancement mode tech-

This family of devices is designed to handle a wide variety of analog switching and driver applications. They are capable of high speed operation where excellent transient response and wide voltage range are required. The SD5000 quad switch array and the SD5100 quad multiplexer can handle high voltage analog signals (±10V), whereas the SD5001 and SD5101 are designed for lower voltage applications. The SD5200 is intended for use as a 30V driver to complement the other switch products.

FEATURES

- LOW INPUT CAPACITANCE 2.4pF
- LOW FEEDBACK CAPACITANCE 0.3pF
- LOW OUTPUT CAPACITANCE 1.3pF
- ±10V ANALOG SIGNAL RANGE
- LOW PROPAGATION DELAY TIME 600ps
- LOW ON RESISTANCE 30 Ω
- LOW FEEDTHROUGH AND FEEDBACK TRANSIENTS
- ION IMPLANTED FOR GREATER RELIABILITY
- HIGH CHANNEL-TO-CHANNEL ISOLATION 107dB
- TRANSIENT PROTECTION FOR GATES

SD5000 APPLICATIONS

ANALOG SWITCHING (UP TO VERY HIGH FRE-QUENCIES)

AUDIO ROUTING

CHOPPERS

CROSSPOINT SWITCHES

SAMPLE AND HOLD

SD5100 APPLICATIONS

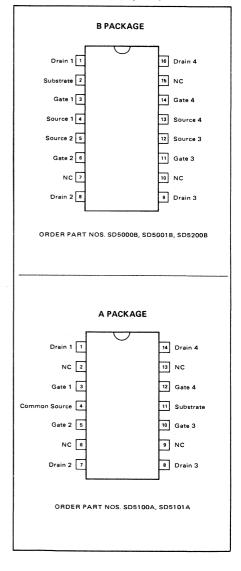
MULTIPLEXING

CURRENT SUMMING

SD5200 APPLICATIONS

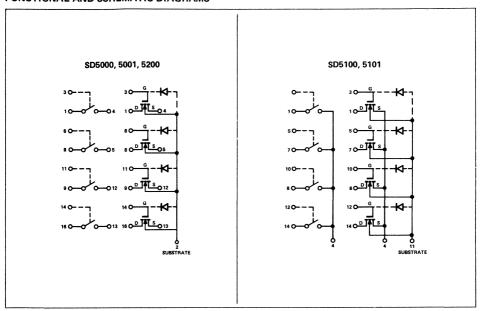
SWITCH DRIVERS

PIN CONFIGURATION (Top View)



SIGNETICS D-MOS FET QUAD ANALOG SWITCH ARRAYS, MULTIPLEXERS AND DRIVER = \$D5000/5001/5100/5101/5200

FUNCTIONAL AND SCHEMATIC DIAGRAMS

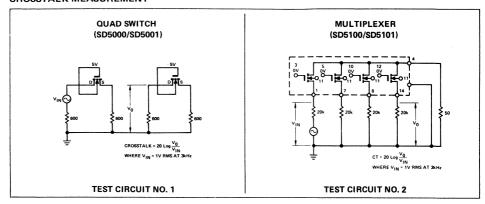


ABSOLUTE MAXIMUM RATINGS T_A = 25°C (Unless Otherwise Noted)

	PARAMETER	SD5000	SD5001	SD5100	SD5101	SD5200	UNITS	
VDS	Drain-To-Source	+20	+10	+30	+15	+30	Vdc	
V_{SD}	Source-To-Drain	+20	+10	+.5	+.5	+.5	Vdc	
V_{DB}	Drain-To-Substrate	+25	+15	+30	+15	+30	Vdc	
V_{SB}	Source-To-Substrate	+25	+15	+.5	+.5	+.5	Vdc	
V _{GS}	Gate-To-Source	+25 -25	+20 -15	+20	+20	+20	Vdc	
V_{GB}	Gate-To-Substrate	+30 -0.3	+25 -0.3	+20 -0.3	+20 -0.3	+20 -0.3	Vdc	
V_{GD}	Gate-To-Drain	+25 -25	+20 -15	+20	+20	+20	Vdc	
ID	Drain Current	50	50	50	50	50	mA	
Ambi	ent Temperature Range							
	Storage			-55 to +150)		°C °C	
	Operating		0 to +85					
Power	r Dissipation			J. J. L. C.				
	Total Package Dissipation* Individual Transistor Dissipation*	640 300					mW mW	

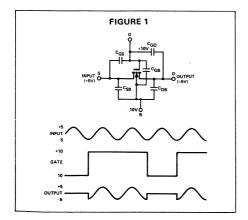
^{*} Derated 5mW per degree centigrade

CROSSTALK MEASUREMENT



THEORY OF OPERATION

The SD5000 series consists of four SPST switches with analog signal capability of up to ±10 volts for the SD5000 and up to ±5 volts for the SD5001. Each switch of the array is a D-MOS N-channel field-effect transistor of the enhancement-mode type; that is, the device is normally off when gate-to-source voltage (VGS) is zero volts. When VGS exceeds the threshold voltage VT the FET switch starts to turn on. With VGS in excess of +10 volts, a low resistance path (typically 30Ω) exists between input and output of the switch. Figure 1 below shows the normal mode of operation of a single switch of the array for $\pm 5\,$ volt analog signal processing. Note that the source is recommended for the input since feedback or reverse transfer capacitance is lower when drain is used as the output. In this case, the switch is driven by ±10 volts for which the SD5200 could be used as discussed later.



When analog signals are routed from one point to another the important factors are isolation, cross-talk between switches, feedthrough and feedback transients, insertion loss and speed of operation. The SD5000 series offers superior performance in all these areas.

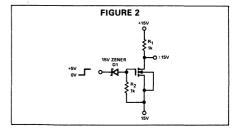
Isolation. ON resistance is typically 30Ω and OFF resistance is typically $10^{10}\Omega$, which means the OFF to ON resistance ratio is in excess of 10^9 . Isolation from output to input from 3kHz analog signals is –107dB.

Feedback and feedthrough transients. These are kept to a minimum because of the very low feedback and feedthrough capacitances. This means that "glitchless" or "clean" signals appear at the output.

Insertion loss. This depends upon the source and load impedances involved. As an example for 600Ω source impedance the insertion loss for voice signals (1V RMS at 3kHz) is less than 0.3dB. This indicates that the SD5000 series would make good telephone cross-point switches.

Speed. Because of the low ON resistance and low input capacitance the SD5000 switches turn on at sub-nano-second speeds. They are also capable of handling very high frequency analog signals and still maintain excellent isolation (20-30dB at 1GHz).

The SD5200 is intended as a driver for the SD5000/5001 but is capable of driving any system which requires ± 15 volts. Four drivers are in each package and Figure 2 shows how a single driver is biased for ± 15 volts. Two external resistors R₁, R₂ and a zener diode D₁ are required per driver. The input is 5V open collector TTL.



SIGNETICS D-MOS FET QUAD ANALOG SWITCH ARRAYS. MULTIPLEXERS AND DRIVER = SD5000/5001/5100/5101/5200

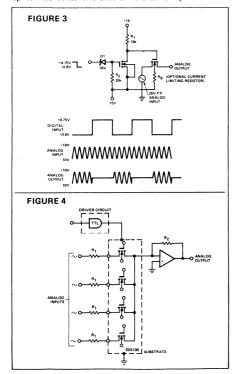
The SD5100 series is four channel multiplexers. The SD5100 has 0-30 volts input voltage capability and the SD5101 has 0-15 volts input voltage capability. Each circuit has a common source. The signals at the source are limited to $\pm 200 \text{mV}$ and therefore these circuits are used where switching is performed at the virtual ground point of an op amp. In this case, no external driver is required nor are any additional power supplies required. Because the ON resistance of both the SD5000 and SD5001 is very low (30 Ω typ) and matched within 5Ω , the need for a compensating FET is minimized and in some cases eliminated. The parts can be driven directly from TTL, either +5 volts or +15 volts open collector.

ANALOG SWITCH/DRIVER APPLICATION

The SD5200 operates as an inverting switch capable of driving 30 volts maximum. This wide range capability with high speed fulfills most analog switching applications. Figure 3 demonstrates how the SD5200 drives the SD5000 in a typical analog switching application.

ANALOG MULTIPLEXER APPLICATION

The SD5100 series is easy to use as shown in Figure 4. Drive circuitry can be TTL or if very low R_{ON} is required (19 Ω typ), then TTL open collector logic can drive the SD5100 up to +20 volts. The common source is kept at or near



ELECTRICAL CHARACTERISTICS TA = +25°C

	Р	ARAMETER
	Breakdown Volt	age
	BVDS	Drain-To-Source
	BV _{SD}	Source-To-Drain
	BV _{DB}	Drain-To-Substrate
	B∨ _{SB}	Source-To-Substrate
	Leakage Current	
	I _{DS} (OFF)	Drain-To-Source
	I _{SD} (OFF)	Source-To-Drain
	I _{GBS}	Gate
	I _{GB}	Gate-To-Substrate
	V _T	Threshold Voltage
	gfs	Forward Transconductance
	Small Signal Cap	acitances
	C(GS + GD + GB)	
	C(GD + DB)	Drain Node
	C(GS + SB)	Source Node
	C _{DG}	Reverse Transfer
	CT	Cross Talk
	r _{DS} (ON)	Drain-To-Source Resistance
·	r _{DSM} (ON)	Resistance Match

ground and each drain will withstand +30 volts with isolation typically 120dB.

If a compensation transistor is required in series with $R_2,$ then the maximum mismatch error for R_1 = R_2 = $10k\Omega$ would be:

SIGNETICS D-MOS FET QUAD ANALOG SWITCH ARRAYS, MULTIPLEXERS AND DRIVER = SD5000/5001/5100/5101/5200

TEST CONDITIONS		SD5000)	SD5001		SD5100		SD5101		SD5200)	UNITS			
	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
				γ			r									
V _{GS} = V _{BS} = -5V, I _S = 10nA	20	25		10	25											V
$V_{GS} = V_{BS} = 0V, I_{S} = 1\mu A$ $V_{GS} = V_{BS} = 0V, I_{S} = 10\mu A$							30	35		15	30		30	35		V
$V_{GD} = V_{BD} = -5V, I_D = 10nA$	20			10									30	33		V
$V_{GD} = V_{BD} = 0V, I_{D} = 10nA$	20			10			.5			.5						V
V _{GB} = 0V, Source OPEN																
I _D = 10nA	25			15												V
I _D ≈ 1μA				1			30			15						V
V _{GB} ≈ 0V, Drain OPEN															-	
I _S = 10μA	25			15			_			_						V
I _S = 100nA	L			L			.5			.5			L			
V _{GS} = V _{BS} = -5V	Ι			T			Γ			Ι			l			
V _{DS} = +20V		1	10													nΑ
V _{DS} = +10V	1	,			1	10										nA
V _{GS} = V _{BS} = 0V, V _{DS} = +10V								1	10		1	10				nA
V _{GD} = V _{BD} = -5V																
V _{SD} = +20V	1	1	10							1						nA
V _{SD} = +10V					1	10				1						nA
V _{DB} = V _{SB} = 0V																
V _{GB} = 25V V _{GB} = 20V			10			10			40							μΑ
	l					10			10			10			10	μΑ
Drain and Source OPEN			_													
V _{GB} = +30V V _{GB} = +25V			1	l		1										μΑ
				 									-			μΑ
$V_{DS} = V_{GS} = V_{T}, I_{S} = 1\mu A, V_{SB} = 0V$	0.1	1.0	2.0	0.1	1.0	2.0	0.5	1.0	2.0	0.5	1.0	2.0	0.5	1.0	2.0	V
				 			 			-			 			
$V_{DS} = 10V, V_{SB} = 0V,$ $I_{D} = 20mA, f = 1kHz$	10	15		10	15		10	15		10	15		10	15		mmhos
				L			L			L			<u> </u>			
$V_{DS} = 10V$, $f = 1MHz$,																
V _{GS} = V _{BS} = -15V	τ												,			
See Capacitance Model		2.4	3.5		2.4	3.5		2.4	3.5		2.4	3.5		2.4	3.5	pF
in Figure 1		1.3	1.5		1.3	1.5		1.3	1.5		1.3	1.5		1.3	1.5	pF
		3.5	4.0	1	3.5	4.0										pF
		0.3	0.5		0.3	0.5		0.3	0.5		0.3	0.5		0.3	0.5	pF
See Test Circuits No. 1 & 2, f = 3kHz								-107								dB
I _D = 0.1mA, V _{SB} = 0								-								
V _{GS} = +5V								50	70							Ω
V _{GS} = +10V								30	45							Ω
V _{GS} = +15V V _{GS} = +20V								23 19								Ω
	ļ												т			
ID = 0.1mA, VSB = 0,								1	5					_		Ω
V _{GS} = +5V	1												1			1

$$error = \frac{R_2 + 65\Omega}{R_1 + 70\Omega} = .05\%$$

Without the compensation transistor the error would be:

error =
$$\frac{R_2}{R_1 + 70\Omega}$$
 = .7%

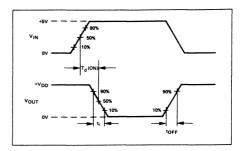
SIGNETICS D-MOS FET QUAD ANALOG SWITCH ARRAYS, MULTIPLEXERS AND DRIVER = SD5000/5001/5100/5101/5200

SWITCHING CHARACTERISTICS

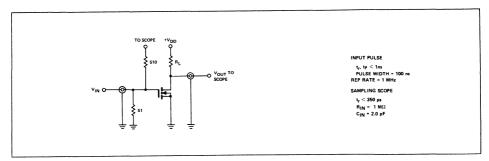
		t _d (O	N) (ns)	t _r	(ns)	tOFF (ns)		
V_{DD}	RL	TYP	MAX	TYP	MAX	TYP	MAX	
5	680	0.6	1.0	0.7	1.0	9.0	*	
10	680	0.7		0.8		9.0		
15	1k	0.9		1.0		14.0		

 $^{^{\}rm t}{\rm OFF}$ is dependent on R $_{\rm L}$ and C $_{\rm L}$ and does not depend on the device characteristics.

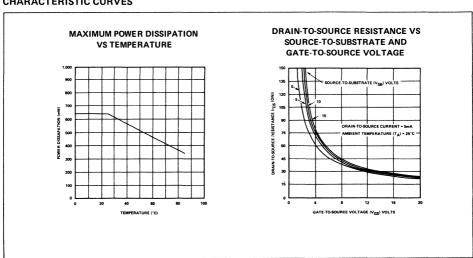
SWITCHING WAVEFORMS



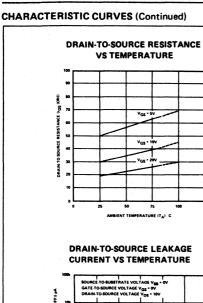
TEST CIRCUIT

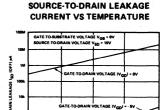


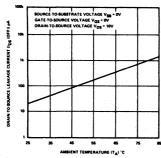
CHARACTERISTIC CURVES



SIGNETICS D-MOS FET QUAD ANALOG SWITCH ARRAYS, MULTIPLEXERS AND DRIVER = SD5000/5001/5100/5101/5200

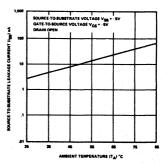




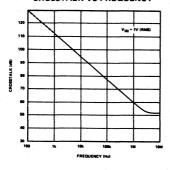


SOURCE-TO-SUBSTRATE LEAKAGE **CURRENT VS TEMPERATURE**

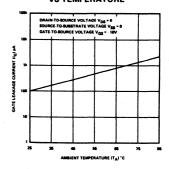
NT TEMPERATURE (TA) °C



CROSSTALK VS FREQUENCY



GATE LEAKAGE CURRENT VS TEMPERATURE





D-MOS DUAL - GATE FETS | SD6000 N-CHANNEL ENHANCEMENT

FM AND VHF FRONT-END APPLICATIONS

DESCRIPTION

The Signetics D-MOS SD6000 is an integrated circuit fabricated by the double-diffused process and employing silicon N-channel enhancement mode MOSFETs with dual gates. Zener diodes are connected between all gates and the substrate. These diodes bypass any voltage transients which lie outside the range of -0.3V to +20.0V. Thus, the gates are protected against damage in all normal handling and operating situations. The use of the dual gate structure plus the incorporation of the drift region has made the feedback capacity (CG1D) typically less than 0.03pF. The attributes of the IC make it ideally suited for FM/VHF RF amplifier and mixer applications. The IC is specifically characterized for incorporation into varactor or conventional FM tuners but the performance guaranteed makes it useful in a wide variety of VHF tuner applications. The power gain at 100MHz is 30dB minimum with a guaranteed noise figure of 3.0dB. A wide AGC capability plus significant reduction in cross modulation is now available because of the inherent linearity of the D-MOS FETs. The SD6000 is packaged in the Signetics 8-pin plastic V package.

GENERAL FEATURES

- POSITIVE BIAS ONLY
- LOW GATE VOLTAGES
- ENHANCEMENT MODE OPERATION
- ZENER DIODE GATE PROTECTION
- ION IMPLANTED FOR GREATER RELIABILITY

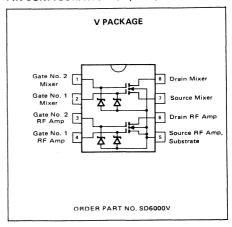
FEATURES (RF AMP Section)

- HIGH POWER GAIN WITHOUT NEUTRALIZATION 25dB AT 100MHz
- LOW NOISE FIGURE 2.5dB AT 100MHz
- LOW INPUT AND OUTPUT CAPACITANCES CON-STANT WITH AGC - 3.0pF AND 1.0pF
- LOW FEEDBACK CAPACITANCE 0.025pF
- SUPERIOR CROSS MODULATION PERFORMANCE
- HIGH TRANSCONDUCTANCE 15mmhos
- WIDE AGC BANGE 50dB AT 100MHz

FEATURES (Mixer Section)

• HIGH CONVERSION GAIN - 17dB AT 100MHz WITH VG1S = VG2S FOR BIASING SIMPLICITY

PIN CONFIGURATION (Top View)



- EXCELLENT ISOLATION FROM GATE NO. 1 (RF) TO GATE NO. 2 (LO)
- LOW INPUT CAPACITANCE 4.0pF
- LOW FEEDBACK CAPACITANCE 0.03pF
- **EXCELLENT CROSS MODULATION PERFORMANCE** AND LOW NOISE OPERATION
- HIGH CONVERSION TRANSCONDUCTANCE AT LOW DRAIN CURRENTS - 10mmhos

ABSOLUTE MAXIMUM RATINGS

T_A = 25°C (Unless Otherwise Noted)

V_{DS} Drain-To-Source Voltage

+20V

V_{G1B} Gate No. 1-To-Substrate Voltage V_{G2B} Gate No. 2-To-Substrate Voltage -0.3 to +20Vdc -0.3 to +20Vdc

Drain Current

50mA

Ambient Temperature Range Storage

Operating

-65°C to +150°C -65°C to +125°C

P_T Power Dissipation

At 25°C Case Temperature Temperature Above 25°C

625mW Derate at 5.0mW/°C

ELECTRICAL CHARACTERISTICS TA = 25°C

PARAMETER		TEST CONDITIONS		LIMITS					HAUTE
				MIN		TYP		AX	UNITS
OFF Cha	aracteristics — RF Amp and	Mixer							
BV _{DS}	Drain-To-Source Breakdown Voltage	$V_{G1S} = V_{G2S} = 0V, I_D = 5\mu A$		20		30			٧
I _{D(OFF)}	Drain-To-Source Leakage Current	V _{DS} = +15V, V _{G1S} = V _{G2S} = 0V			0.	.001	1	.0	μΑ
I _{D SS}	Zero Bias Drain Current	V _{DS} = +15V, V _{G1S} = V _{G2S} = 0V			0.	001	1	.0	μΑ
I _{G1SS}	Gate No. 1 Leakage Current	$V_{G1S} = +5V, V_{G2S} = V_{DS} = 0V$			0.	001	0.1		μΑ
I _{G2SS}	Gate No. 2 Leakage Current	$V_{G2S} = +10V, V_{G1S} = V_{DS} = 0V$			0.	.001	0.1		μΑ
ON 01			В	F AM	P		MIXE	R	
ON Chai	racteristics		MIN	TYP	MAX	MIN	TYP	MAX	
V _{T1}	Gate 1 Threshold Voltage	$V_{DS} = V_{G1S} = V_{T1},$ $V_{G2S} = +10V, I_D = 1\mu A$	0.1	0.5	1.5	0.1	1.0	2.0	v
V _{T2}	Gate 2 Threshold Voltage	$V_{DS} = V_{G2S} = V_{T2},$ $V_{G1S} = +5V, I_D = 1\mu A$	0.1	0.5	1.5	0.1	1.0	2.0	V
r _{DS(ON)}	Drain-To-Source On Resistance	V _{G1S} = +5V, V _{G2S} = +10V, I _D = 0.1mA		65	100		30	60	Ω
Small Si	gnal Characteristics — RF A	mp		MIN	1	TYP	М	AX	
gfs	Forward Transconductance	V _{DS} = +15V, V _{G2S} = +10V, I _D = 18mA, f = 1kHz		12		15			mmhc
Capacita	nces	f = 1MHz, Gate No. 2 AC Grounded							
C _{G1S}	Input	V _{DS} = +15V, V _{G2S} = +10V, I _D = 18mA				3.0	3	.5	рF
CDS	Output	V _{DS} = +15V, V _{G1S} = 0V, V _{G2S} =	= 10V			1.0	1	.3	pF
C _{G1D}	Reverse Transfer	V _{DS} = +15V, V _{G1S} = 0V, V _{G2S} =	10V		0	.025			pF
Re (y ₁₁					1	0.21			
Im (y ₁₁	Admittance				İ	2.26			
Re (y ₂₂ Im (y ₂₂	}	f = 100MHz, V _{DS} = +15V			- 1	0.20 0.68			mmho
Re (y ₂₁		V _{G2S} = +10V, I _D = 18mA			1	2.85			
	Transmittance					1.50			
Re (y ₁₂ Im (y ₁₂					1	0.01 0.03			
Gps	Power Gain*	V _{DS} = +15V, V _{G2S} = +10V I _D = 18mA, f = 100MHz		20		25			dB
NF	Noise Figure*	V _{DS} = +15V, V _{G2S} = +10V I _D = 18mA, f = 100MHz				2.5	3	3.0	dB
AGC(V	Gain Control	V _{DS} = +15V, V _{G1S} ≅+2.5V, f = 100MHz				50			dB

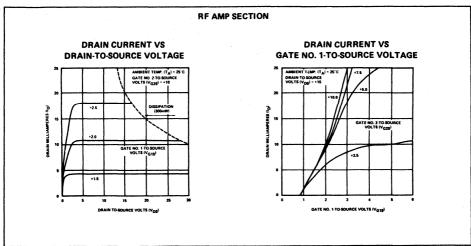
SIGNETICS D-MOS DUAL DUAL-GATE FETS, N-CHANNEL ENHANCEMENT = SD6000

ELECTRICAL CHARACTERISTICS (Continued) TA = 25°C

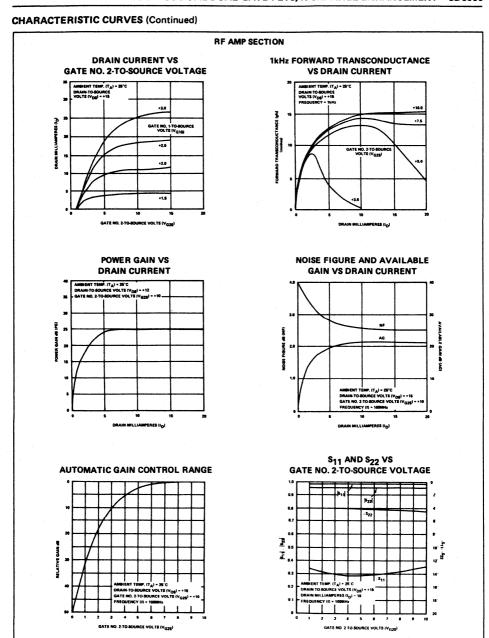
0.0.0.05750	TEST CONDITIONS				
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Small Signal Characteristics — MIXE	R				
gfs(CONV) Conversion Transconductance	V_{DS} = +15V, V_{G1S} = V_{G2S} I_D = 8mA, f = 1kHz E_{LO} (RMS) = 750mV		10		mmhos
Capacitances	f = 1MHz, Gate No. 2 AC Grounded				
C _{GIS} Input	$V_{DS} = +15V$, $V_{G1S} = V_{G2S}$, $I_D = 8mA$		4.0	4.75	pF
C _{DS} Output	V _{DS} = +15V, V _{G1S} = V _{G2S} = 0V		1.1	1.5	pF
C _{G1D} Reverse Transfer	V_{DS} = +15V, V_{G1S} = V_{G2S} = 0V		0.030		pF
Input Admittance			0.21		
Re (y ₁₁) Im (y ₁₁)			2.28		
Output Admittance Re (y ₂₂)			0.41		
Im (y ₂₂) Forward Transmittance	f = 100MHz, V _{DS} = +15V V _{G1S} = V _{G2S} , I _D = 8mA		1.04		
Re (y ₂₁) im (y ₂₁)	1013 10237.0 5		3.18 -0.83		
Reverse Transmittance Re (y ₁₂) Im (y ₁₂)			0.03 -0.01		
Gps _(CONV) Conversion Power Gain**	V_{DS} = +15V, V_{G1S} = V_{G2S} , I_{D} = 8mA, f_{RF} = 100MHz, f_{LO} = 89.3MHz	14	19		dB

^{*}Measured in Amplifier test fixture.

CHARACTERISTIC CURVES



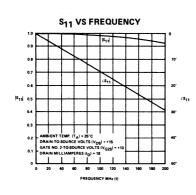
^{**}Measured in MIXER test fixture.

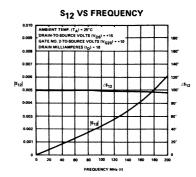


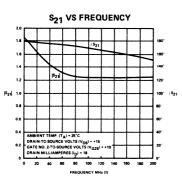
SIGNETICS D-MOS DUAL DUAL-GATE FETS, N-CHANNEL ENHANCEMENT = SD6000

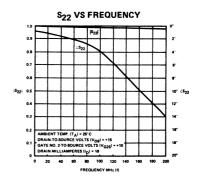
CHARACTERISTIC CURVES (Continued)

RF AMP SECTION



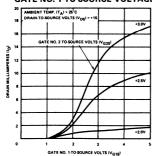




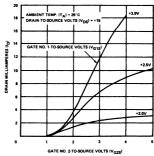


MIXER SECTION

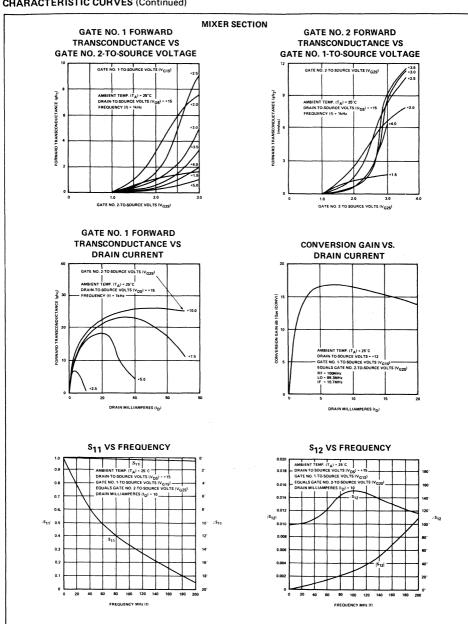
DRAIN CURRENT VS
GATE NO. 1-TO-SOURCE VOLTAGE



DRAIN CURRENT VS GATE NO. 2-TO-SOURCE VOLTAGE

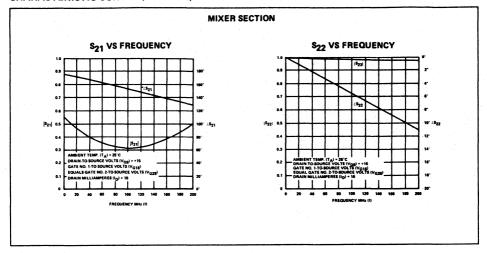


CHARACTERISTIC CURVES (Continued)

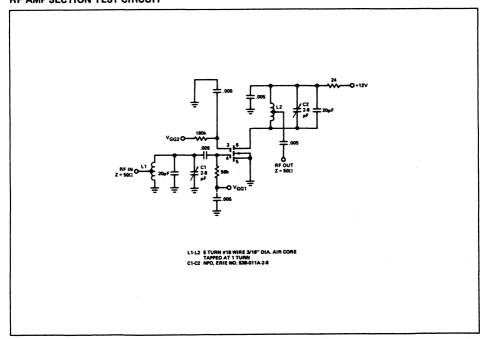


SIGNETICS D-MOS DUAL DUAL-GATE FETS, N-CHANNEL ENHANCEMENT = SD6000

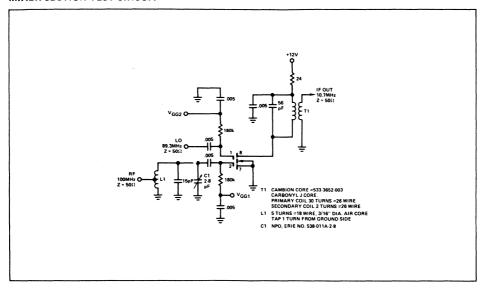
CHARACTERISTIC CURVES (Continued)



RF AMP SECTION TEST CIRCUIT



MIXER SECTION TEST CIRCUIT

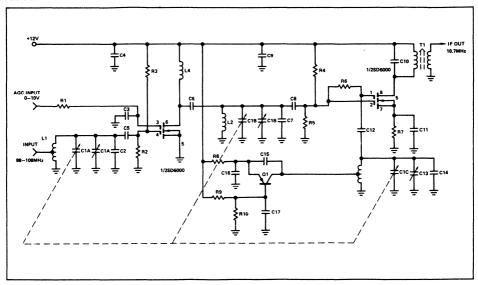


FM TUNER USING SD6000 ELECTRICAL DATA

PARAMETER	TEST CONDITIONS	TYP
Supply Voltage		+12V
Supply Current	AGC voltage +10V	25mA
Frequency Range		88MHz to 108MHz
Bandwidth	RF Amp (-3dB) Mixer (-3dB)	2.5MHz 300kHz
Input Impedance		75Ω
Output Impedance		50Ω
IF Output Frequency		10.7MHz
Oscillator Stability w/respect to Supply Voltage		40kHz/volt
Oscillator Stability w/respect to Temperature		10kHz/°C
Power Gain	88MHz to 108MHz	30dB Min
Noise Figure	@ 100MHz	3.0dB Max

SIGNETICS D-MOS DUAL DUAL-GATE FETS, N-CHANNEL ENHANCEMENT = SD6000

FM TUNER USING SD6000



PARTS LIST

1. Transistors	Descrip	tion Type	C3, 4,	5, 6, 8, .0	05	+80% - 20% Ceramic	
Q1	PNP Silicon	n 2N4126		9, 11, 12, 17 C7 10c		TEN NIDO	
2. Integrated Circ	uits		C10		OpF SpF	±5% NPO ±5% MICA or Ceramic	
U1	Dual D-MO	S FET SD6000V	C13		8pF	Trimmer	
3 Resistors (All	carbon resistors	in ohms ±10% tolerance.)	C14	1:	2pF	±5% NPO	
O. Hadiston (7111		olillib = 1070 tolol diloci,	C15	10	0pF	±5% NPO	
	Value		C16	10	0pF	±5% NPO	
R1	30k						
R2	68k						
R3	200k		5 Miccel	Innanua Comi	onent-		
R4	150k		5. Miscellaneous Components				
R5	39k		T1	IF Transfo	rmer	Cambion 533-3652-003	
R6	82k					Jcore Prim. 30T #26	
R7	120					Sec. 2T #26	
R8	6800		L1	RF Input (Coil	4 turns #18 on 3/16"	
R9	13k					dia. Air core Tap 1	
R10	3k					turn from ground side.	
4. Capacitors			L2	RF Output	Coil	4 turns #18 on 3/16"	
	Value	Туре				dia, air core.	
C1	5-20pF	3 Gang Tuning Capacitor	L3	Oscillator (Coil	4 turns #18 on 3/16"	
C2	20pF	±5% NPO				dia, air core center-tapped,	
			L4			33µh RF choke	

signetics

APPLICATIONS MEMO

SD6000

LINEAR DEVICES FM TUNER

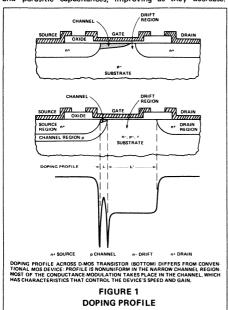
INTRODUCTION

Signetics dual D-MOS FETs are dual gate n-channel enhancement mode MOSFETs fabricated by a new state-of-the-art technique. They make it possible for the tuner designer to obtain the high performance typical of D-MOS at a cost competitive with bipolars. Dual gate D-MOS has inherently linear characteristics making it especially suitable in FM tuner RF stages where high RF and conversion gain, low noise figure, wide dynamic range, and excellent cross-modulation and intermodulation characteristics are necessary.

CONSTRUCTION

An understanding of the basic differences in the construction of Signetics D-MOS vs. the conventional MOSFET is very helpful in realizing the maximum benefits of D-MOS.

Construction of D-MOS transistors is basically different from a conventional n-channel MOSFET in that it contains a lowly doped region of length L' between the channel p region and the highly n doped drain contact region, as shown in Figure 1. Generally, MOS transistor frequency response is directly related to channel length (L) and parasitic capacitances, improving as they decrease.



D-MOS construction permits a precisely controlled L of less than 1 micron, extremely low parasitic capacitances and additionally, no restriction on maximum drain breakdown voltage. Although the construction differs, operation of D-MOS is similar to that of ordinary MOSFETs. Positive voltage applied between gate and source controls the number of carriers in the channel, and therefore, the conductivity.

FM TUNER DESIGN

The purpose of this design was to build an FM tuner using dual gate D-MOS FETs, in an economical epoxy package, to verify their superior performance. Careful consideration was given to the problems involved in putting two devices in the same package. The die were placed in the package in a manner that minimizes the coupling from one device to the other. This was done to keep the L.O. isolated from the RF input and for stability.

The AC performance characteristics of the SD6000 given on the data sheet are used for this design. The input and output matching networks are designed using scattering parameters.

This data is given below in Figure 2.

	(MHz)	911	^S 12 (dB)	³ 21 (dB)	³ 22
RF Amp	100	.984-14	-50∠80	3∠ 165	.98∠-6
Mixer	100	.98∠-18	-47∠90	-5.2∠ 150	.96∠-6
		FIGL	IRF 2		

SD6000 S-PARAMETERS

The s-parameters given in Figure 2 can be readily converted to y-parameters. The RF amplifier can then be designed using classical "two port network" theory. A problem exists, however, when the s-parameters $(S_{11} \text{ and } S_{22})$ magnitudes are very close to unity. When this is the case, a small change in magnitude of S_{11} or S_{22} gives a large change in Y_{11} and Y_{22} . For example, the s-parameters given for the RF amplifier device in Figure 2 give

$$Y_{11} = .2 + j 2.43 \text{ (mmhos)}$$

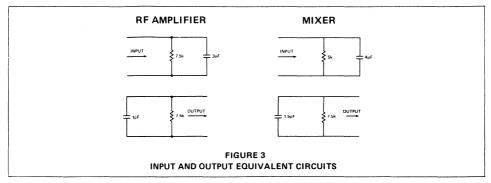
 $Y_{22} = .2 + 1.03 \text{ (mmhos)}$

If S₁₁ and S₂₂ are equal to .99 instead of .98 we get

$$Y_{11} = .1 + j 2.43 \text{ (mmhos)}$$

 $Y_{22} = .1 + j 1.03 \text{ (mmhos)}$

This means that a 1% error in measuring S_{11} or S_{22} will give a 2 to 1 change in the real part of the devices' input or output impedance. This makes a paper design questionable unless some assumptions are made. For this tuner design the device input and output equivalent circuits were approximated as shown in Figure 3:



These approximations make the design much easier and were verified by the final tuner performance.

INPUT CIRCUIT

The high input impedance of the SD6000 makes it possible to have a high Q input circuit. This makes the tuner very selective and free from spurious responses. Figure 4 shows the equivalent input circuit.

A 70 nh inductor was chosen to allow the tuner to cover the FM band with a ΔC of \approx 18pF. The required capacitance ratio can be found in the following way:

$$\omega_1 = 2\pi f_1$$
 $\omega_1 = \text{radian frequency at the low end of the FM band.}$

$$\omega_2$$
 = $2\pi f_2$ ω_2 = radian frequency at the high end of the FM band.

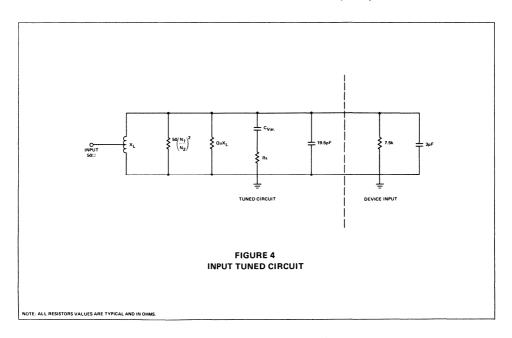
$$\omega_1^2 = \frac{1}{LC_1}$$
 C_1 = required capacitance at low frequency.

$$\omega_2^2 = \frac{1}{LC_2}$$
 C_2 = required capacitance at high end.

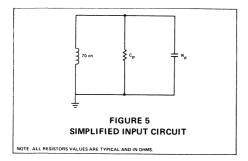
Therefore
$$\omega_1^2 C_1 = \omega_2^2 C_2$$

or
$$\frac{C_1}{C_2} = \frac{{\omega_2}^2}{{\omega_1}^2} = \frac{4.6 \times 10^{17}}{3.05 \times 10^{17}} = 1.46:1$$

A capacitance ratio of 1.6 was used to assure covering the FM band with component parameter variations.



The equivalent circuit can be further simplified as shown in Figure 5.



 $C_{\boldsymbol{p}}$ is made up of the D-MOS input capacitance, a fixed parallel capacitor, and the varactors. The maximum $C_{\boldsymbol{p}}$ required is

$$C_{p_1} = \frac{1}{\omega_1^2 L} = 47.5 pF.$$

Of this total the capacitance of the varactor is approximately 28pF. This corresponds to a tuning voltage of approximately 2.5V for the varactors used (MV104). Dual varactors in a back-to-back configuration were used so nonlinearities caused by the diodes would cancel.

The minimum Cp required (at 108 MHz) is

$$C_{p_2} = \frac{1}{\omega_2^2 L} = 31 pF.$$

The capacitance of the varactor should now be approximately 11.5pF, corresponding to a tuning voltage of 20 volts. The choice of this tuning voltage range is quite arbitrary and just depends on the type of varactors used. For the automobile radio market, a lower voltage varactor could be used. It is possible to tune 88 → 108 MHz with 2 to 10 volts using commercially available varactors.

 R_p in Figure 5 is made up of the equivalent parallel resistance of the device input and the parallel resistance of the varactors and the inductor. In this case R_p is approximately equal to 7.5k (device), 5.7k (inductor), and 50k (varactor). This 3.05k parallel resistance is matched to the antenna impedance (in this case it was matched to a 50Ω generator) by tapping the inductor. The required turns ratio is $(3050/50)^{1/2}$ or approximately 7:1.

The bandwidth of the input circuit can be found knowing the total parallel resistance and parallel capacitance

$$B\omega_{3dB} = \frac{1}{2\pi RC} = \frac{1}{2\pi \times 2k \times 40pF}$$
(at 100 MHz) 3 MHz

This bandwidth is narrow enough to provide good rejection to signals outside the FM band but wide enough to avoid tracking problems.

OUTPUT CIRCUIT

The design of the output circuit is very similar to that of the input. The only difference is a different value of fixed capacitance to take into account the RF amplifier output capacitance and that of the mixer input,

GAIN AND STABILITY

Dual gate D-MOS transistors are exceptionally stable RF devices because of the low feedback capacitance (.02pF typical). This makes it possible to achieve high gain without the need for neutralization. Low feedback also makes AGC possible over a wide dynamic range.

In the FM band, the SD6000 is not unconditionally stable. k, the stability factor, (inverse of Linvill stability factor) is approximately .36. To assure stability, without neutralization, the gain should be limited to about 20dB. In this design the approach chosen was to mismatch the RF amplifier output and the mixer input. This is done by connecting the RF output tank circuit directly to the mixer input (gate 1). This mismatch limits the RF amplifier gain to 18dB and gives a stability factor of 1.27, assuring stable operating conditions

AGC

Another advantage of the SD6000 is that the input impedance remains essentially constant with AGC level. This means that bandwidth and center frequency do not shift. Figure 6 shows the bandpass characteristics of the completed tuner as different AGC voltages are applied to gate 2 of the RF amplifier.

Figure 7 shows the bandpass characteristics as the RF input frequency is changed.

MIXER

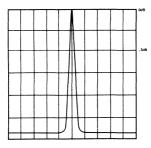
The second dual gate D-MOS transistor in the package is used for a mixer. This device was designed especially for mixer applications, and has a wide square law region. The L.O. is injected in gate two and the input signal in gate one. Injecting the L.O. at gate 2 provides the highest isolation of the L.O. signal to the RF input. This isolation is very important because of restrictions on the amount of L.O. power that may be radiated from the tuner antenna.

The mixer was designed to operate in the most linear portions of the forward transconductance curves. Figures 8 and 9 show the transconductance curves for the SD6000 are linear in a fairly wide operating region, making this device ideal for mixing. Non-linearities in these curves indicate that third order (and higher) terms would be present if the device was biased in these regions. These higher order terms contribute only to undesired responses. As the transconductance curves become linear, the higher order terms disappear and conversion gain increases.

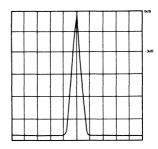
Figure 8 shows that the gate 1 transconductance curve is almost a straight line for gate 2 bias voltages between 2.0

and 6.0 volts. Figure 9 shows the gate 2 transconductance is linear for gate 1 bias from 2.5 to 3.5 volts.

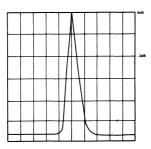
FIGURE 6
AGC/BANDWIDTH CHARACTERISTICS



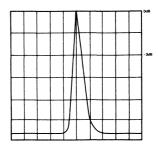
6A. fo = 100 MHz fif = 10.7 MHz (1 MHz/cm) V_{AGC} = 10V Gain Reduction = 0dB



6B. fo = 100 MHz fif = 10.7 MHz (1 MHz/cm) V_{AGC} = 3.9v Gain Reduction = 10dB



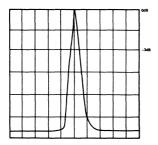
6C. fo = 100 MHz fif = 10.7 MHz (1 MHz/cm) V_{AGC} = 2.6v Gain Reduction = 20dB



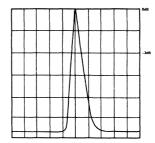
6D. fo = 100 MHz fif = 10.7 MHz (1 MHz/cm) V_{AGC} = 1.8v Gain Reduction = 30dB

FIGURE 6 AGC/BANDWIDTH CHARACTERISTICS

(Continued)

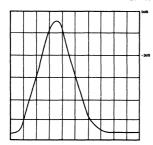


6E. fo = 100 MHz fif = 10.7 MHz (1 MHz/cm) V_{AGC} = 1.3v Gain Reduction = 40dB

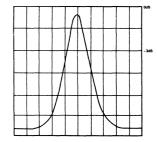


6F. fo = 100 MHz fif = 10.7 MHz (1 MHz/cm) V_{AGC} = 0.9v Gain Reduction = 50dB

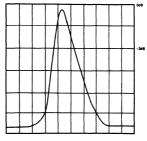
FIGURE 7 BANDWIDTH CHARACTERISTICS



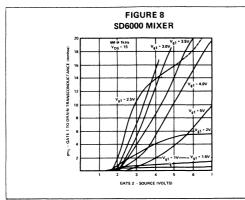
7A. fo = 88 MHz x = 300 kHz/cm $V_{AGC} = 10v$ $V_{Tuning} = 3.0v$

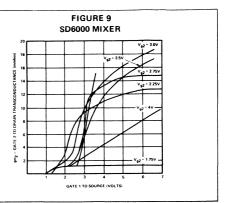


7B. fo = 100 MHz x = 300 kHz/cm $V_{AGC} = 10v$ $V_{Tuning} = 9.8v$



7C. fo = 108 MHz x = 300 kHz/cm $V_{AGC} = 10v$ $V_{Tuning} = 21.9v$





By definition the transconductance, gm is the partial derivative of drain current, i_d, with respect to the input voltage e_s. The total drain current of the mixer can be expressed by

$$i_d = gm_1 V_{g1} + gm_2 V_{g2}$$

where gm₁ = transconductance gate 1 to drain.

gm2 = transconductance gate 2 to drain.

From Figure 8 the gate 1 transconductance, gm_1 can be expressed as:

$$gm_1 = -17.6 + 8.2 (V_{g2} + v_{g2})$$
 (mmhos) for $V_{g2} = 2v$ to $6v$

From Figure 9 we get the following expression for ${\rm gm_2}$

$$gm_2 = -23.7 + 10.2 (V_{g1} + v_{g1})$$
 (mmhos) for $V_{g1} = 2.5v$ to $3.5v$

If the DC bias points are chosen, for example $V_{g1}=3.5$ and $V_{g2}=3.5$, the following expressions are derived from gm_1 and gm_2 using the previous equations

$$gm_1 = 11.1 + 8.2 v_{g2}$$
 (mmhos)
 $gm_2 = 8.9 + 10.2 v_{g1}$ (mmhos)

Substituting these equations into the expression for the total drain current, id, we get

$$i_d = 11.1 v_{g1} + 8.9 v_{g2} + 18.4 v_{g1} v_{g2}$$

The last term in this equation is the one that will contain the IF frequency we desire. If we let $\mathbf{v_{g1}}$ and $\mathbf{v_{g2}}$ equal a sinusoidal voltage, $\mathbf{v_{g1}}$ is the input signal voltage and $\mathbf{v_{g2}}$ is the local oscillator, we obtain

$$v_{g1} = E_s \sin \omega_s t$$

 $v_{g2} = E_{LO} \sin \omega_{LO} t$

Substituting $\mathbf{v_{g\,1}}$ and $\mathbf{v_{g\,2}}$ into the equation for $\mathbf{i_{d}}$ gives

$$i_d = 18.4 E_S E_{LO}$$

[1/2 cos ($\omega_{LO} + \omega_s$) t + 1/2 cos ($\omega_{LO} - \omega_s$)t]

The $(\omega_{LO} - \omega_s)$ term is the 10.7 MHz IF we want. Dividing both sides of the equation by E_s we obtain

$$\frac{I_d}{E_s} = gm_c = 9.2 E_{LO} \text{ (peak)}$$
$$= 13 E_{LO} \text{ (RMS) mmhos}$$

This exercise shows that relatively high conversion gains can be achieved using the SD6000. It can be seen that the conversion transconductance will also be a function of the local oscillator level.

In the tuner that was constructed, a local oscillator level of 800mV RMS was chosen. This gives a conversion transconductance of 10.4 mmhos. The conversion power gain can be calculated by

$$Pg = \frac{|gm_c|^2 R_{in} R_{out}}{4}$$

$$Pg = \frac{[10.4 \times 10^{-3}]^2 [2k] [2k]}{\approx 100 - 20.44 R}$$

This calculated result compares closely with that measured in the actual tuner.

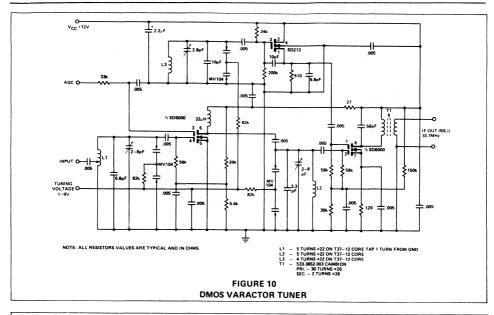
TUNER PERFORMANCE

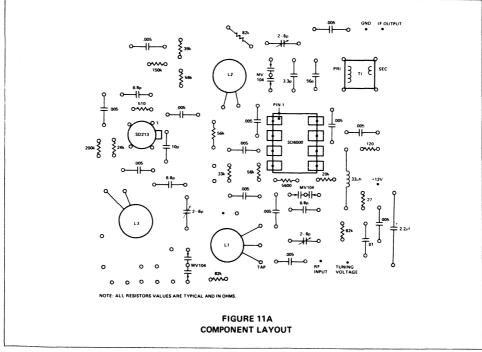
A schematic of the tuner built with the SD6000 is shown in Figure 10. Figure 11 shows the printed circuit board layout.

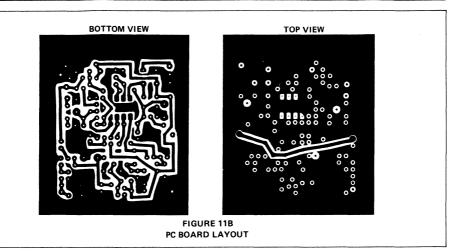
At the present time complete measurements have not been made to verify the tuner performance. A summary of the data that has been measured is given below:

$$V_{Supply}$$
 = +12V
 V_{AGC} = 0 \rightarrow +10V Sensitivity (30dB quieting) $<$ 1.5 μ V

,,,,,			
Frequency (MHz)	Tuning Voltage (VDC)	Gain (dB)	AGC Range (dB)
88	1.2	30	>50
92	2.2	32	>50
96	3.0	34	>50
100	4,1	33	>50
104	5.9	32	>50
108	8.7	31	>50







LOCAL OSCILLATOR

The design of the local oscillator used in this tuner is explained in Appendix A. The SD213 was used because of its linearity and therefore low harmonic generation.

CONCLUSIONS

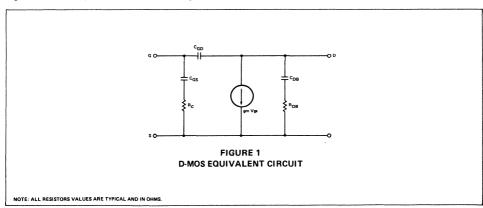
Preliminary performance data indicates that in an FM tuner dual D-MOS will give the high performance required in modern FM radios. The sensitivity and spurious response should exceed that of the best bipolars.

APPENDIX A

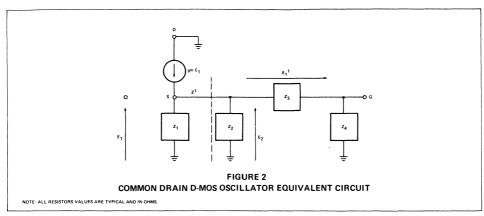
ANALYSIS OF COMMON DRAIN D-MOS OSCILLATOR

This report describes a simplified analysis for a Colpitts oscillator using a Signetics D-MOS transistor in the common drain configuration. The D-MOS device parameters are more stable than those of a bipolar device under temperature and supply voltage variations giving an improvement in frequency stability. The D-MOS devices are also inherently linear and therefore reduce the generation of harmonics of the fundamental oscillator frequency.

Figure 1 shows the equivalent circuit for the dual gate D-MOS transistor.



In this analysis the equivalent circuit shown in Figure 2 will be used. This simplification is justified in this case because the device capacitances are small compared to external capacitances and the equivalent parallel real impedances are very high.



The following analysis will show a solution for Z_1 , Z_2 , Z_3 , and Z_4 which satisfies the Barkhausen criterion for oscillation.

$$Z' = \frac{Z_2 (Z_3 + Z_4)}{Z_2 + Z_3 + Z_4}$$

$$\mathsf{E}_2 = \frac{\mathsf{gm}\;\mathsf{Z}_1\;\mathsf{Z}'\;\mathsf{E}_1}{\mathsf{Z}_1+\mathsf{Z}'}$$

$$E_1' = -\frac{E_2 Z_3}{Z_3 + Z_4}$$

substituting E₂

$$E'_1 = -\frac{gm Z_1 Z' E_1 Z_3}{(Z_1 + Z') (Z_3 + Z_4)}$$

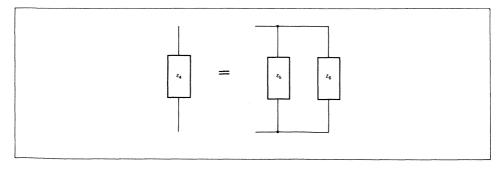
dividing both sides by E1

$$E'_{1} = -\frac{\text{gm Z}_{1} \text{ Z}_{3} \text{ Z}'}{(\text{Z}_{1} + \text{Z}') (\text{Z}_{3} + \text{Z}_{4})}$$

substituting Z'

$$\frac{E_1'}{E_1} = \frac{-\text{ gm } Z_1 \ Z_2 \ Z_3}{Z_1 \ (Z_2 + Z_3 + Z_4) + Z_2 \ (Z_3 + Z_4)}$$

let



then
$$Z_4 = \frac{Z_5 Z_6}{Z_5 + Z_6}$$

substitute
$$Z_4$$
 into $\frac{E_1'}{E_1}$

$$\frac{\mathsf{E}_1'}{\mathsf{E}_1} = \frac{-\mathsf{gm}\,\mathsf{Z}_1\;\mathsf{Z}_2\;\mathsf{Z}_3\;(\mathsf{Z}_5 + \mathsf{Z}_6)}{\mathsf{Z}_1\;[\mathsf{Z}_2\;(\mathsf{Z}_5 + \mathsf{Z}_6) + \mathsf{Z}_3\;(\mathsf{Z}_5 + \mathsf{Z}_6) + \mathsf{Z}_5\;\mathsf{Z}_6] + \mathsf{Z}_2\;[\mathsf{Z}_3\;(\mathsf{Z}_5 + \mathsf{Z}_6) + \mathsf{Z}_5\;\mathsf{Z}_6]}$$

for the Colpitts oscillator configuration choose

$$Z_1 = R$$

$$Z_2 = -jX_2$$

$$Z_3 = -jX_3$$

$$Z_5 = jX_5$$

$$Z_3 = -jX$$

$$Z_5 = jX_5$$

$$Z_6 = -jX_6$$

$$\frac{E_{1}^{\prime}}{E_{1}} = \frac{-gm\ R\ X_{2}\ X_{3}\ (X_{5}-X_{6})}{X_{2}\ [(X_{3}\ (X_{5}-X_{6})+X_{5}\ X_{6}]+jR\ [X_{2}\ (X_{5}-X_{6})+X_{3}\ (X_{5}-X_{6})+X_{5}\ X_{6}]}$$

to satisfy the Barkhausen criterion

$$\frac{\mathsf{E}_1'}{\mathsf{E}_1} = 1 \angle 0^\circ$$

therefore for the imaginary part of $\frac{E_1'}{E_+}$ to be equal to zero

$$X_{2} X_{5} + X_{3} X_{5} + X_{5} X_{6} = X_{2} X_{6} + X_{3} X_{6}$$

or
$$X_5 = \frac{X_6 (X_2 + X_3)}{X_2 + X_3 + X_6}$$

This means that the oscillator frequency will be determined by the series combination of X_2 and X_3 in parallel with X_6 and resonating with X5.

For oscillation to occur the magnitude of $\frac{E'_1}{E_1}$ must be equal to or greater than unity. Therefore

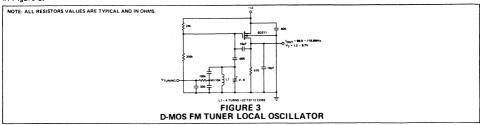
$$\left| \frac{-gmR \ X_2 \ X_3 \ (X_5 - X_6)}{X_2 \ [X_3 \ (X_5 - X_6) + X_5 \ X_6]} \right| \ \geqslant 1$$

which simplifies to

$$gmR \geqslant \frac{X_2}{X_3}$$

or gmR $\geqslant \frac{C_3}{C_2}$ using the expression derived for X₅.

An oscillator for use in a varactor tuned FM receiver was designed using this configuration. A schematic of the circuit is shown in Figure 3.



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